

Operation Experience of the DEPFET based Pixel Vertex Detector of the Belle II Experiment

28th Vertex Conference, 13-18 October 2019

B. Spruck for the Belle II and DEPFET Collaborations



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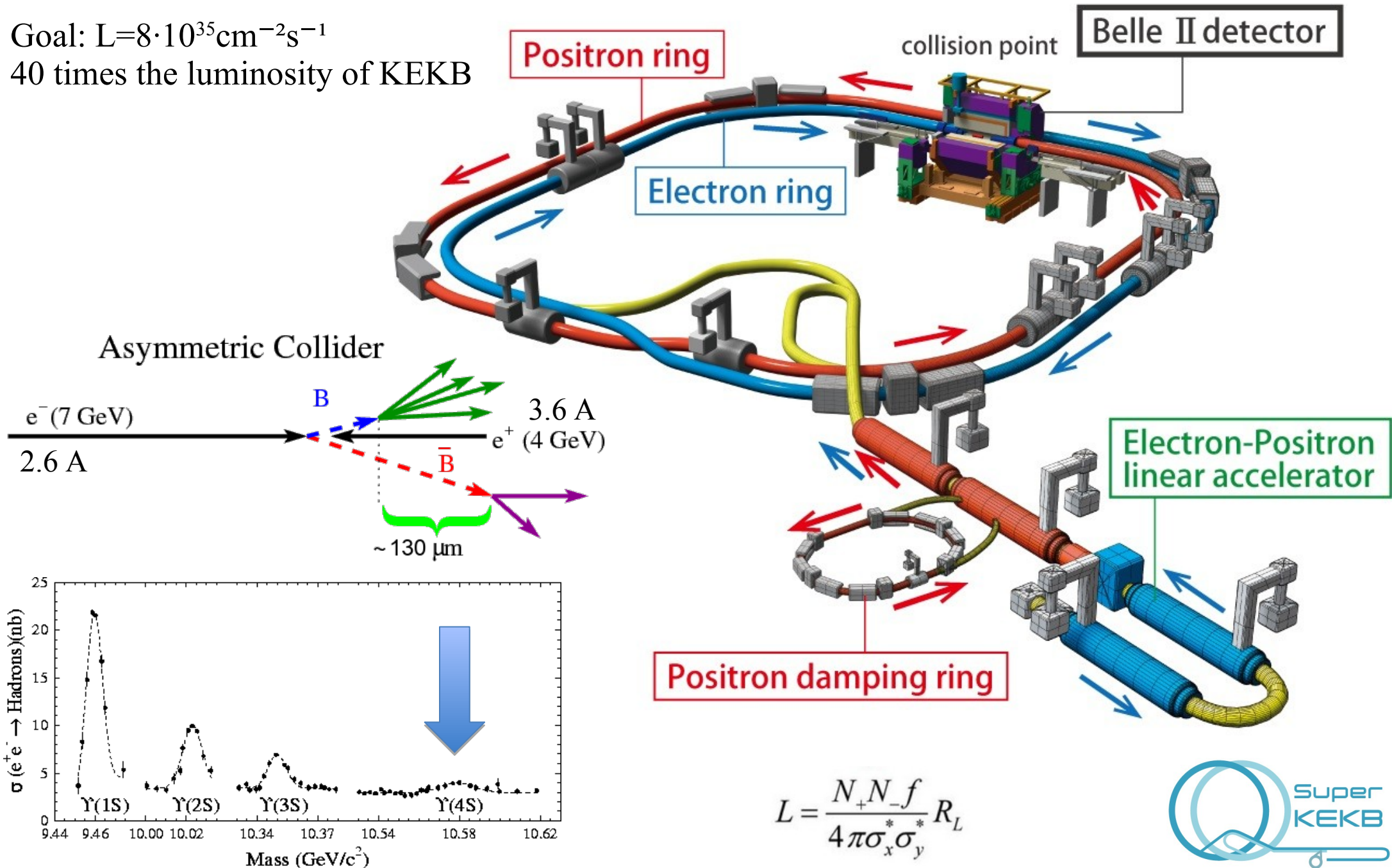


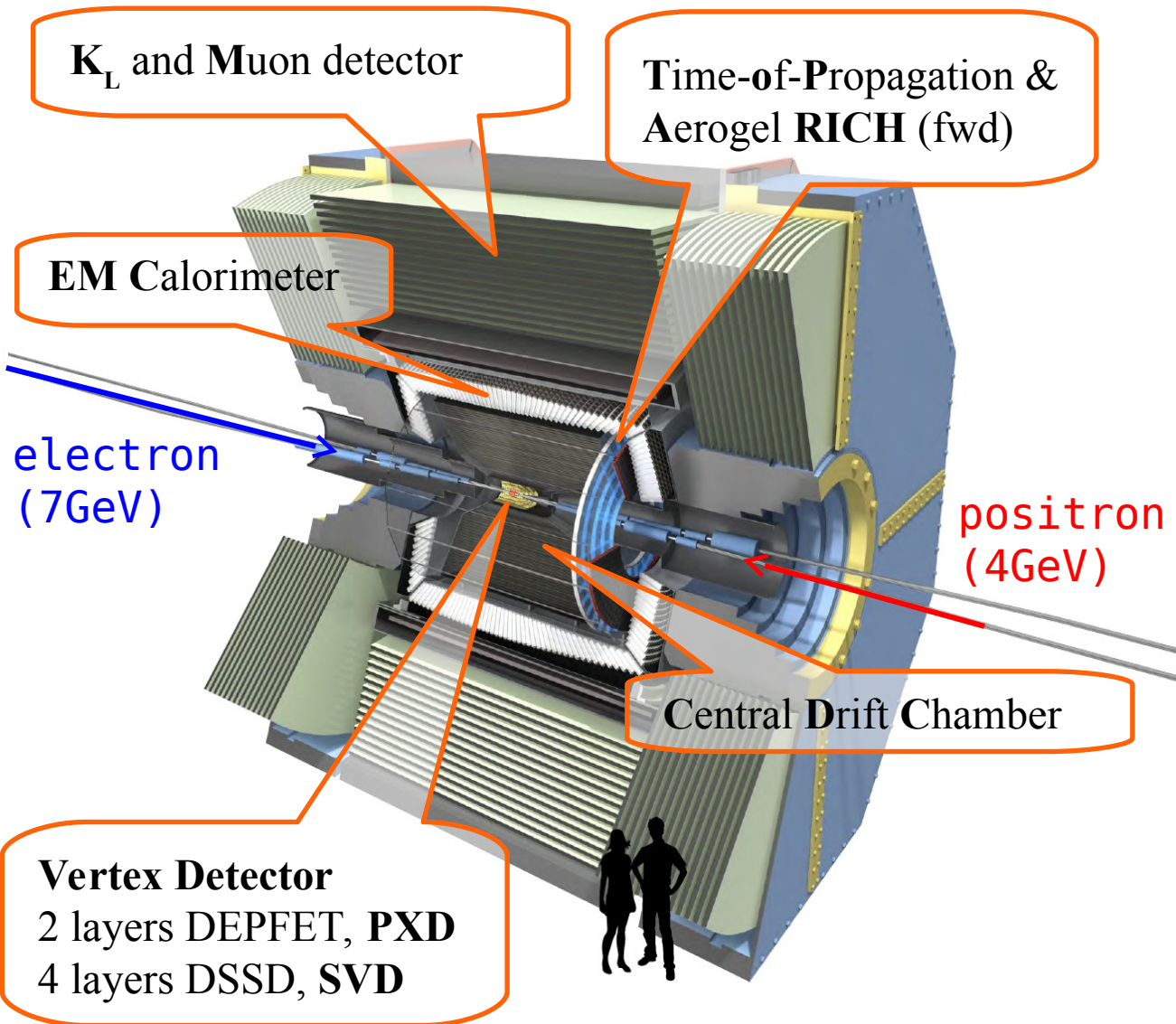
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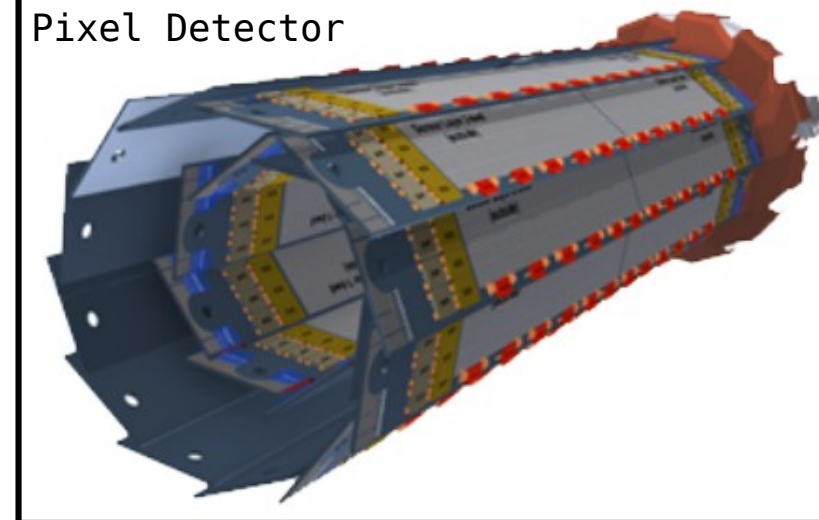
Goal: $L=8 \cdot 10^{35} \text{cm}^{-2}\text{s}^{-1}$
40 times the luminosity of KEKB





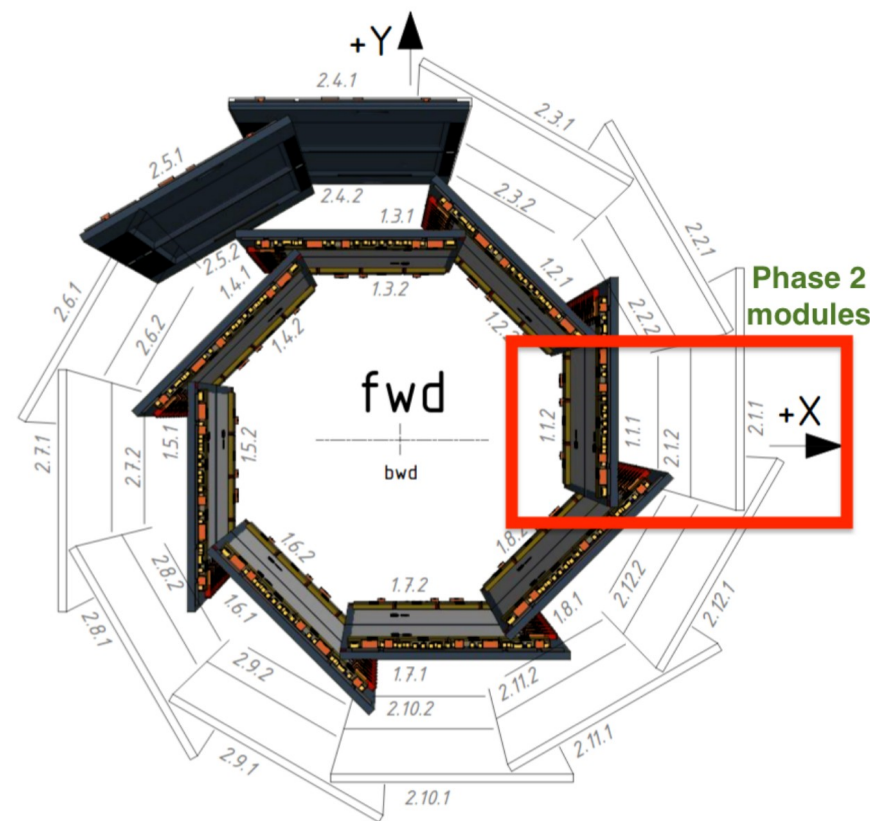
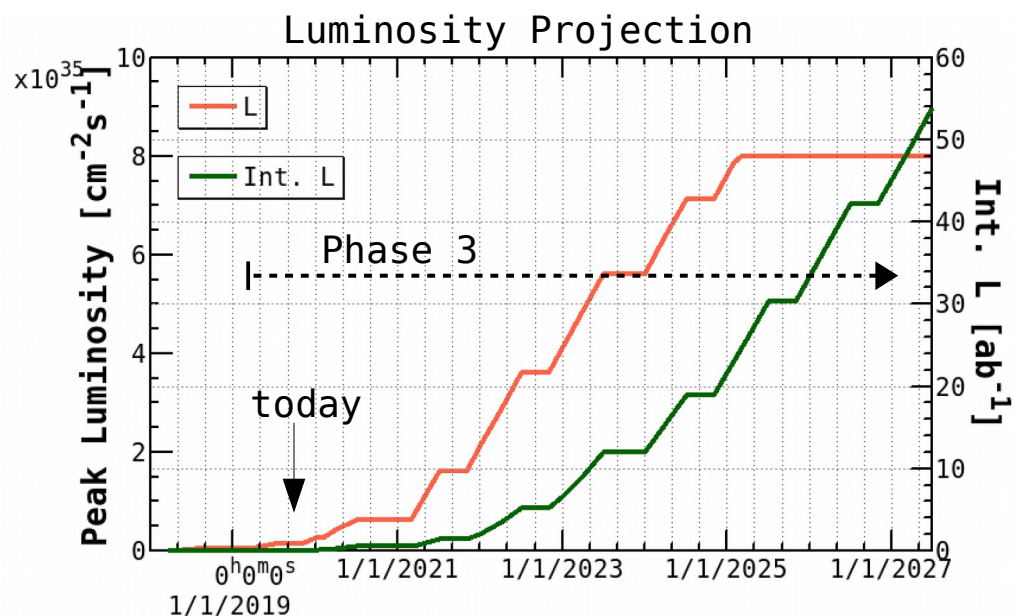
- Excellent vertexing and tracking down to low p_T (<100 MeV/c)
- Very low material budget for vertex detectors
- Inner layer only 14mm away from interaction point
- Impact parameter res. $\sigma_z < 20\mu\text{m}$
- Operate in high background environment
- Trigger rate 30 kHz

Pixel Detector



Physics data taking with full detector started this year

- Phase 1 (2016) – only accelerator commissioning, no Belle II
- Phase 2 (2018) – 1/10 of PXD (1 slice of VXD), “Beast II”
 - Goals: commissioning, safety (beam abort), background, first physics
- Phase 3 (2019) – full VXD (besides PXD, full PXD from 2021)
 - Production delay due to low yield in ladder assembly (solved)
 - Only inner layer + 2 outer ladders were mounted

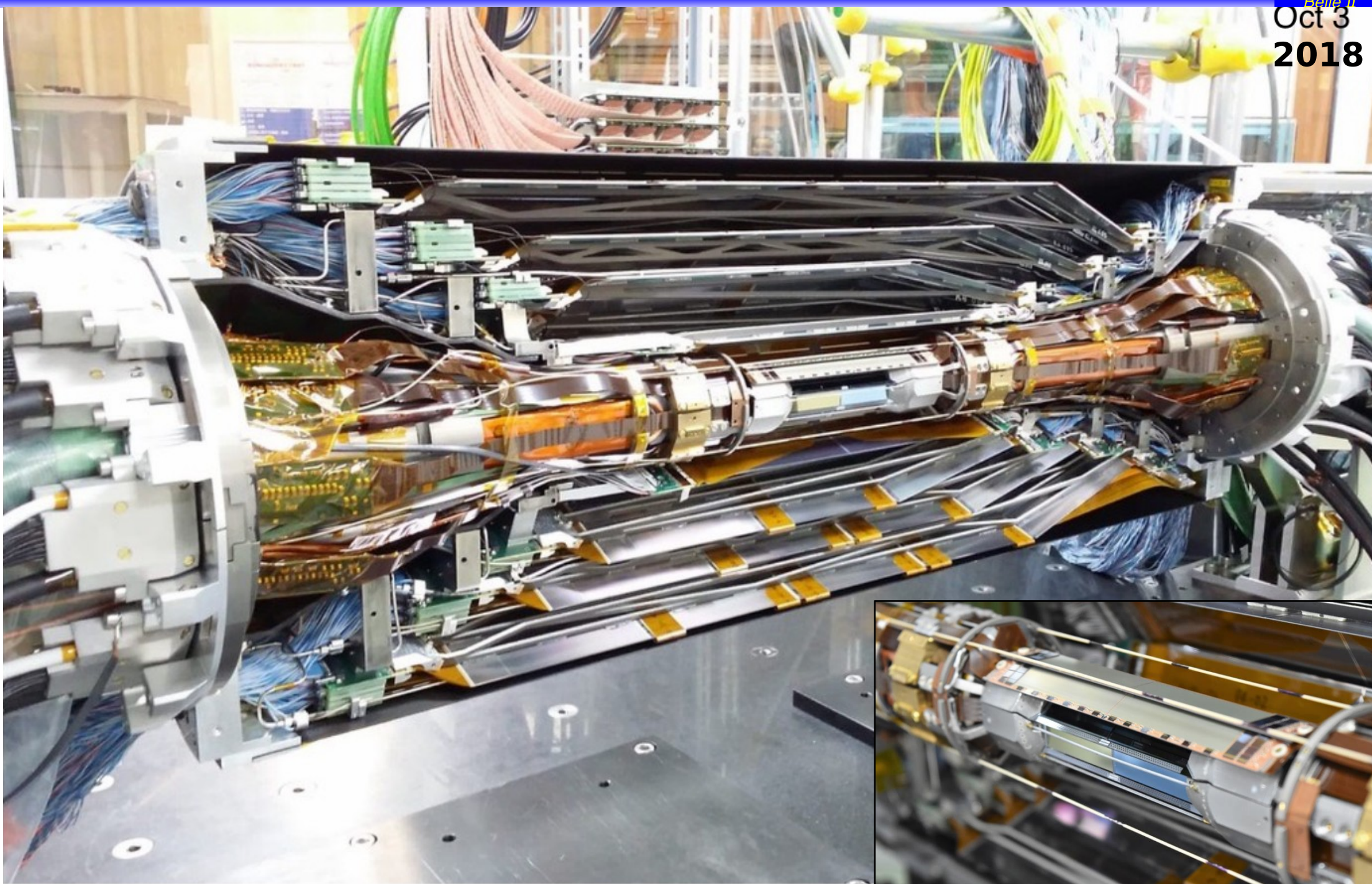


One bad quality module, excluded from DAQ

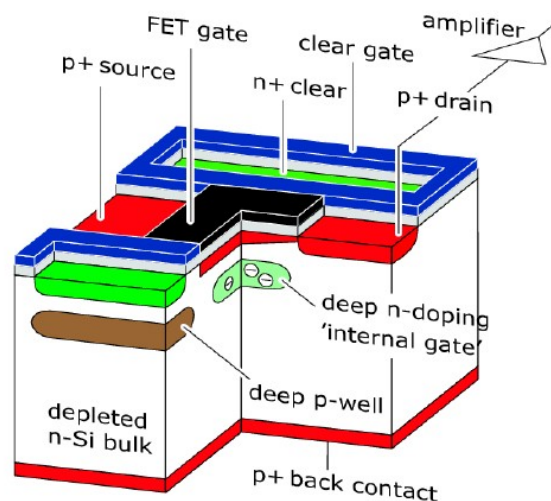
Combining Vertex Detector (One Half Shell)



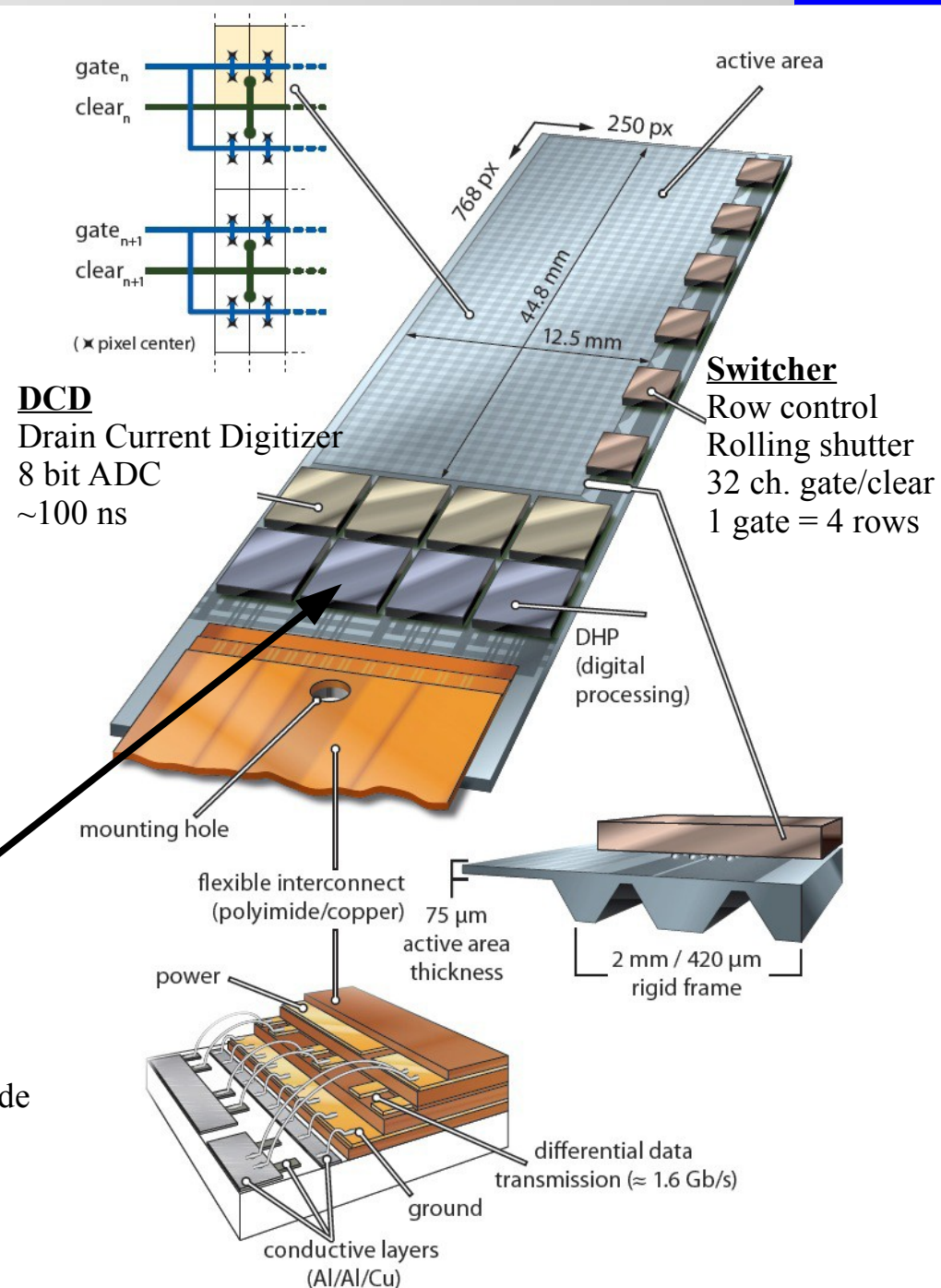
Belle II
Oct 3
2018

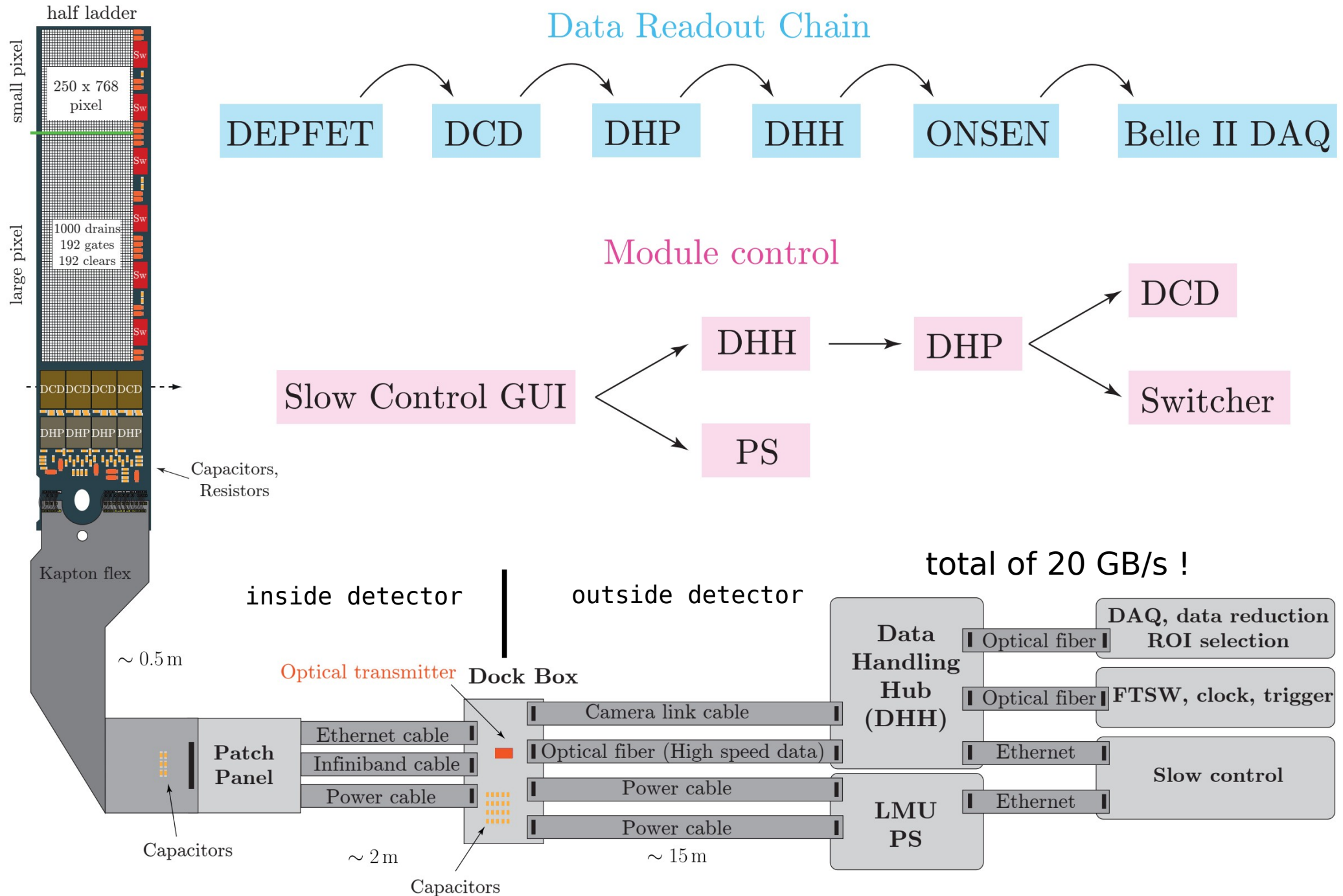


- DEPFET active pixels
- 75 μ m thin sensors
- Pixel size down to 50x55 μ m²
- Rolling shutter read-out \rightarrow low power
 - 50kHz \rightarrow 20 μ s integration time
- Design: 1% occupancy in layer 1
 - 3% occupancy limit (DHP, DAQ, tracking)
- Rad. hard sensor and ASICs
- 40 sensors, 250x768 pixels each



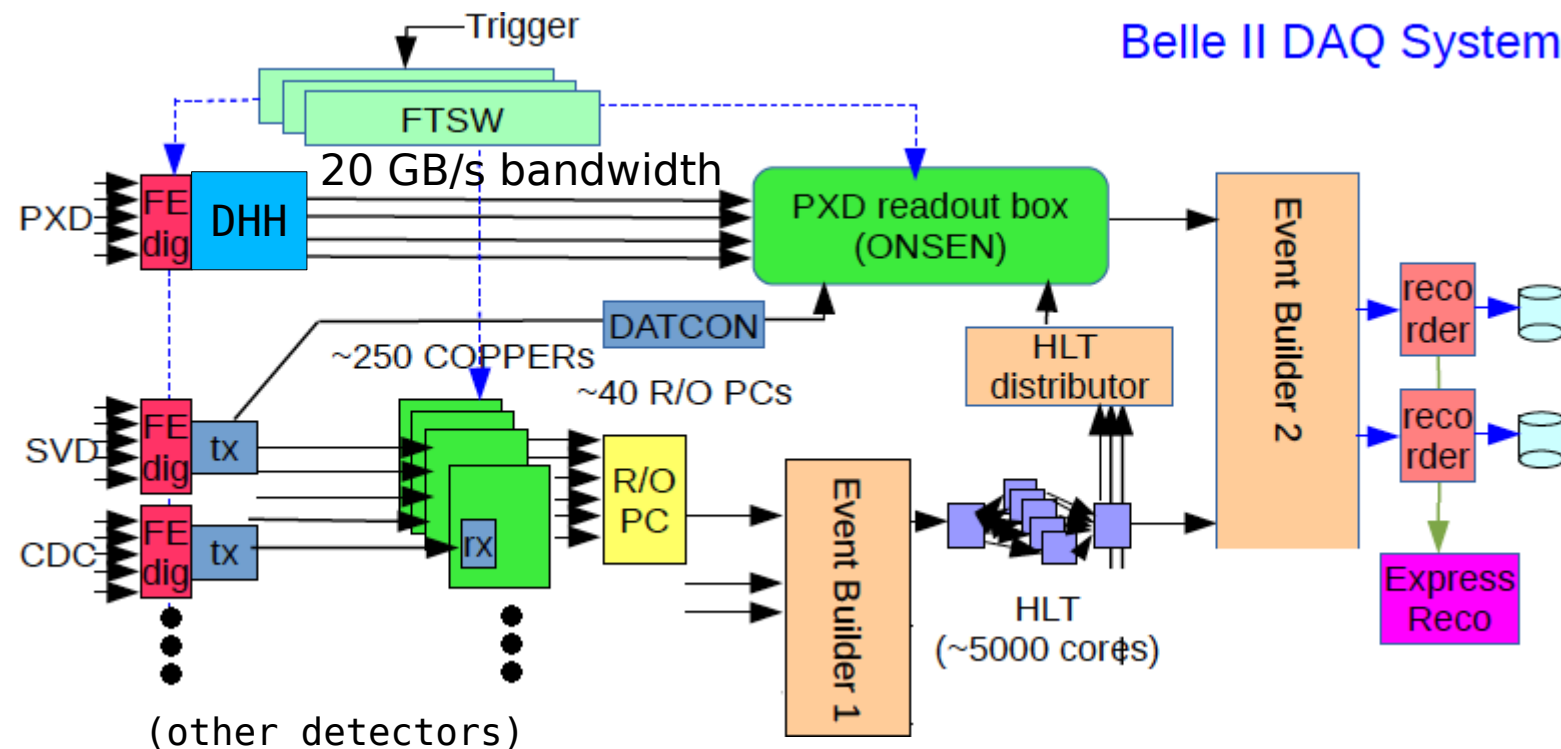
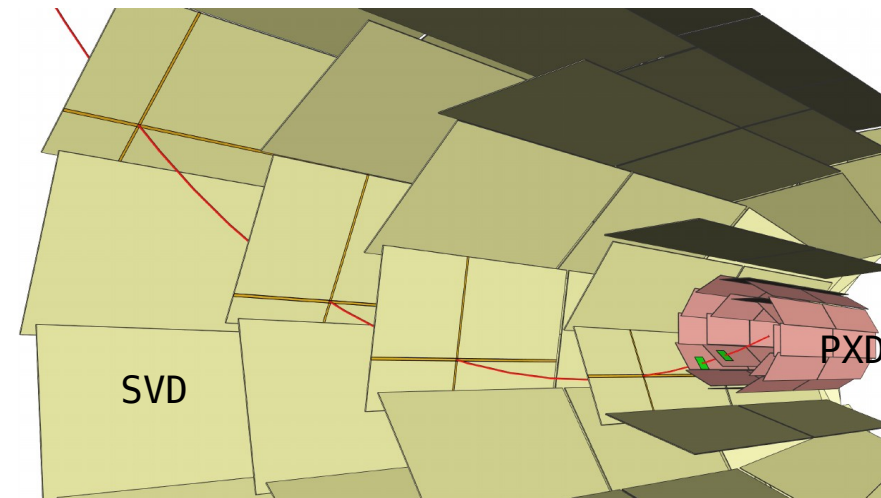
DHP
 Digital processing
 Zero suppression
 Pedestal and common mode correction
 Trigger and timing

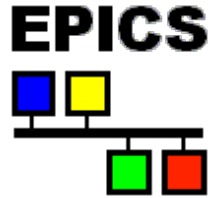




- PXD unfiltered data rate \rightarrow 10x that of other Belle II detectors
 - Separate readout path
 - Remove data not belonging to a track
 - Data reduction to 1/10 by High Level Trigger based “Region Of Interest” calculation from CDC and SVD track information
 - Feedback to PXD readout
 - Selection of pixels within rectangular ROIs

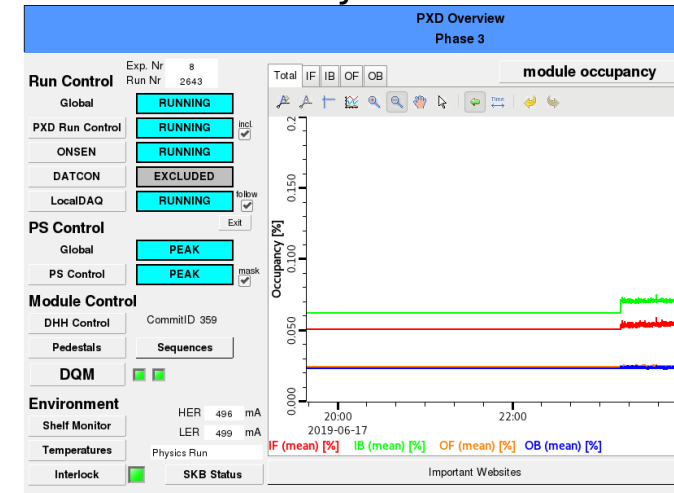
ROI extrapolation on HLT



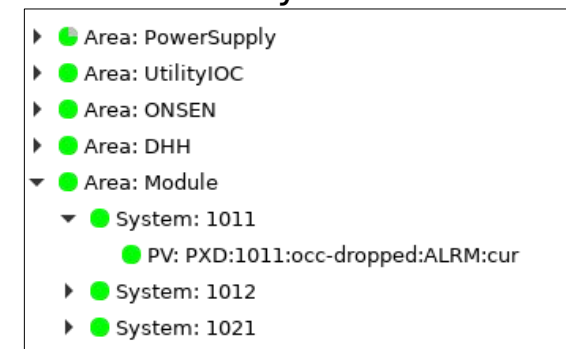


- PXD Slow Control uses EPICS
 - Interfaces to IPBus, IPMI, UNICOS, NSM2, ...
- 20x200 PVs alone from Power Supply control
- Configuration from ConfigDB
 - Sophisticated sequences for powering the modules (ASICs)
- Archiver (13k PVs, 1.4 GB/day)
- Logging: DB with Elasticsearch, elog, Rocket.Chat
- Control and Monitoring GUI
 - Control System Studio
- Alarm System (BEAST)
- Scaled from 4 to 20 (40) modules from Phase 2 → 3

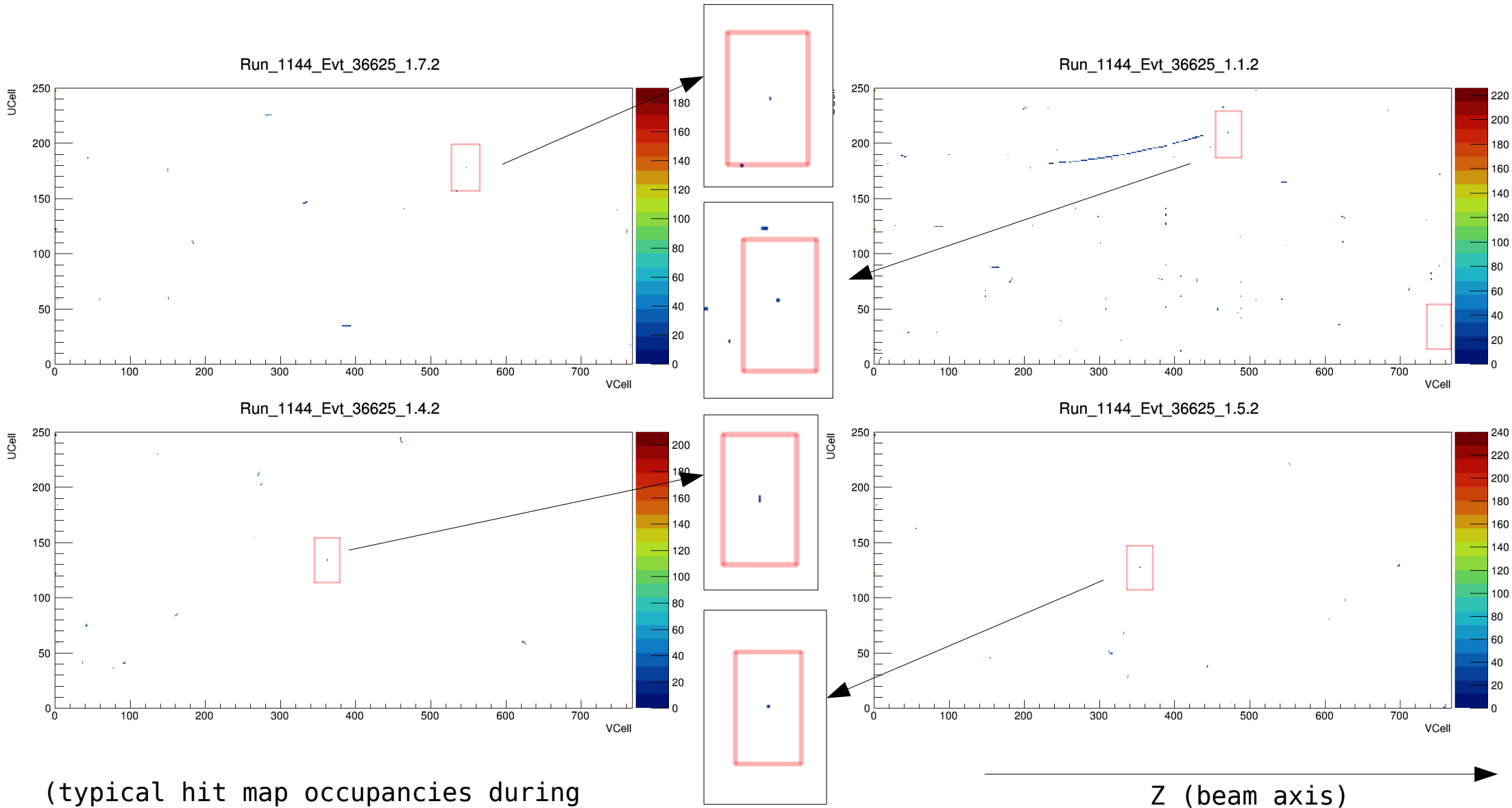
Control System Studio



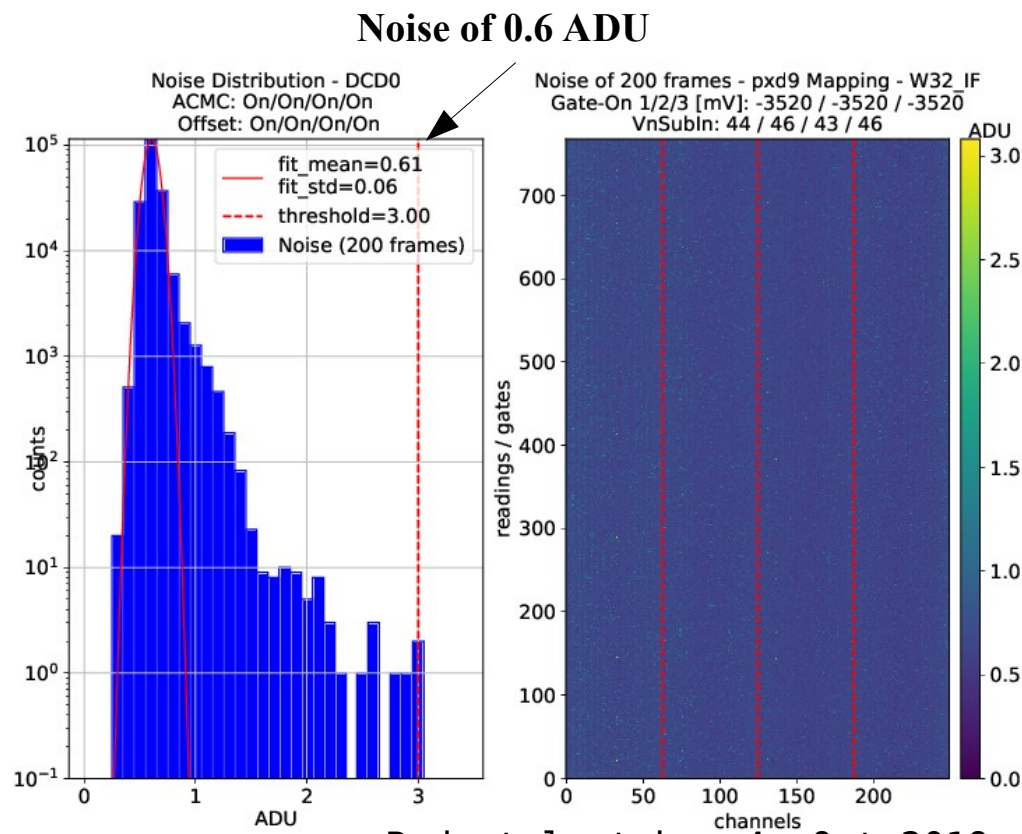
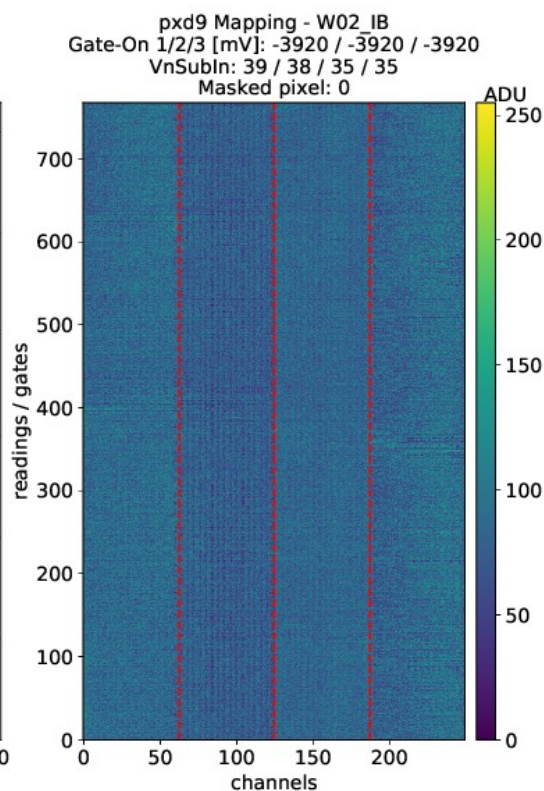
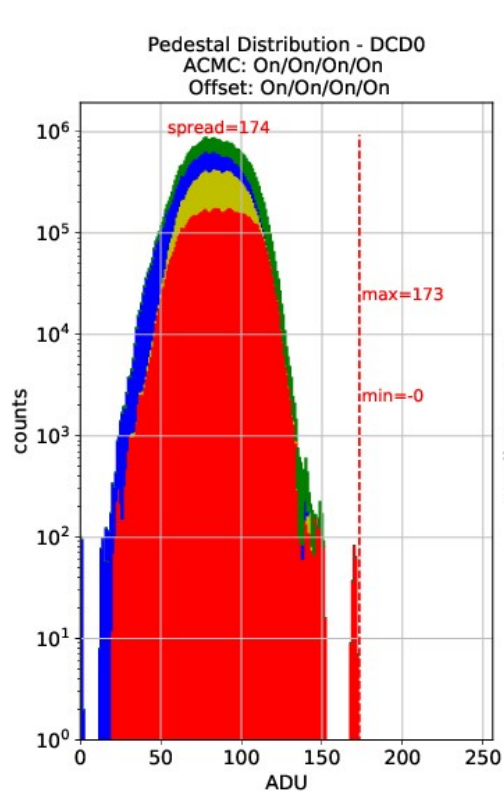
Alarm System Tree



- Region Of Interest selection needs accurate ROI calculation on High Level Trigger
- Hit maps for different modules of same event: clusters fit to ROI computed on HLT

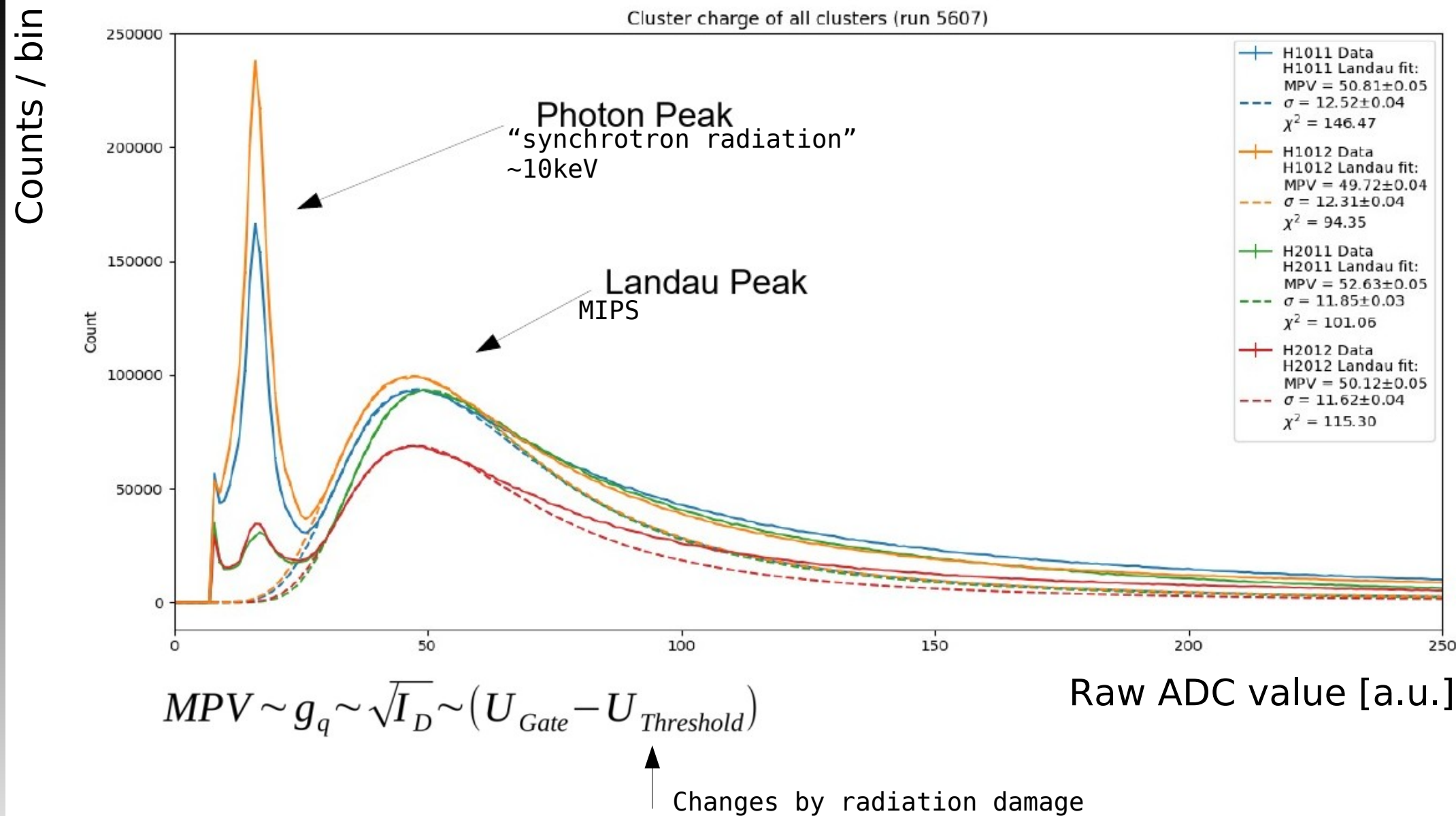


- Phase 3 modules characterized before installation – still need further optimization
- Analog Common Mode Correction
- Switchable currents at input of Drain Current Digitizer used to compress spread of drain currents from sensor
- Narrow and stable pedestals
- Low noise ($<1\text{ADU}$, $<100\text{e ENC}$)



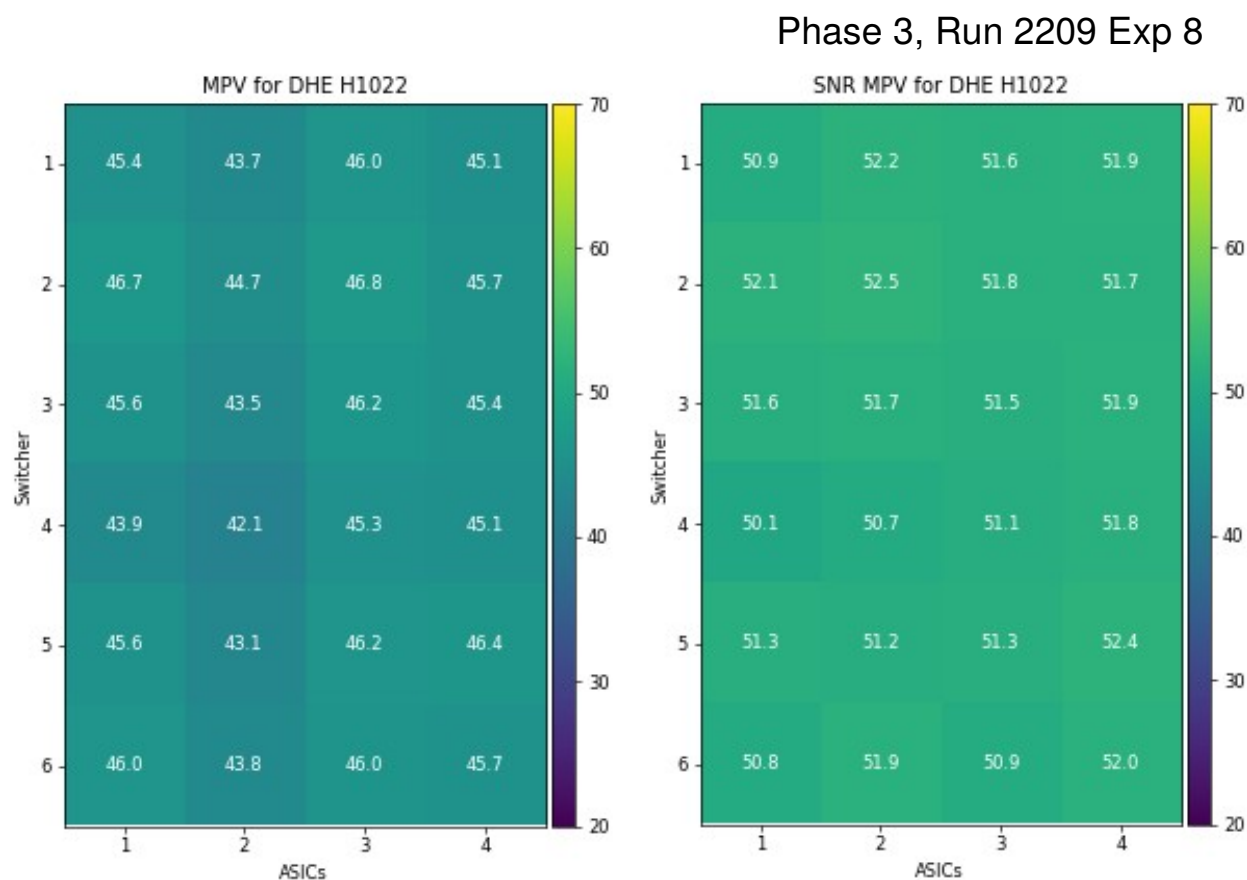
Pedestals taken 4. Oct 2019

Phase 2

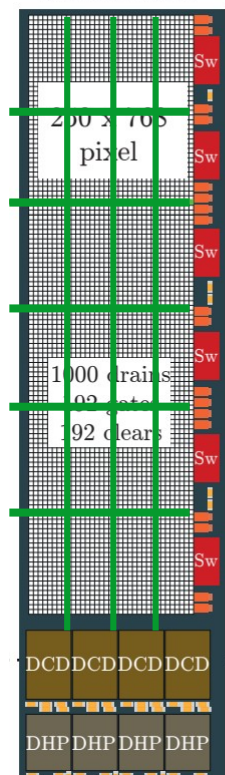


In Phase 3 photons peaks reduced, as Au layer inside beam pipe was thinner in Phase 2 (on purpose)

- Uniform gain over sensor area can be achieved
- Signal to Noise Ratio ≈ 50
- Most probable value and SNR uniform over ASIC combinations

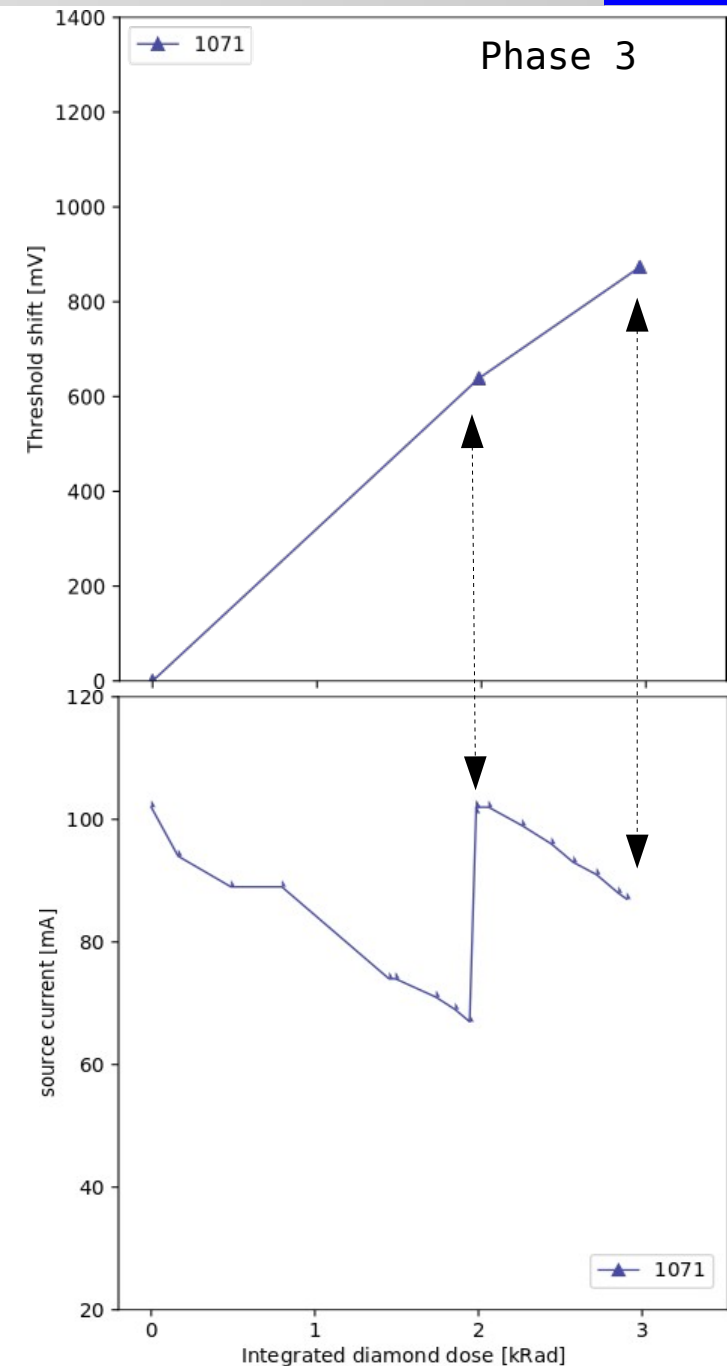
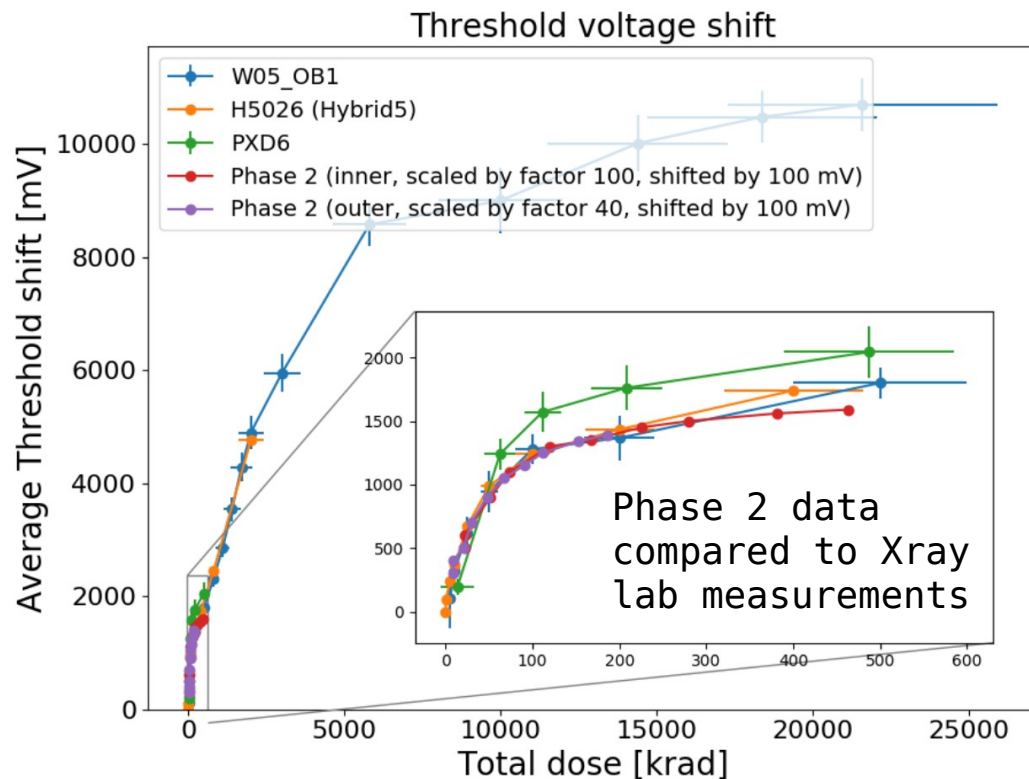


half ladder



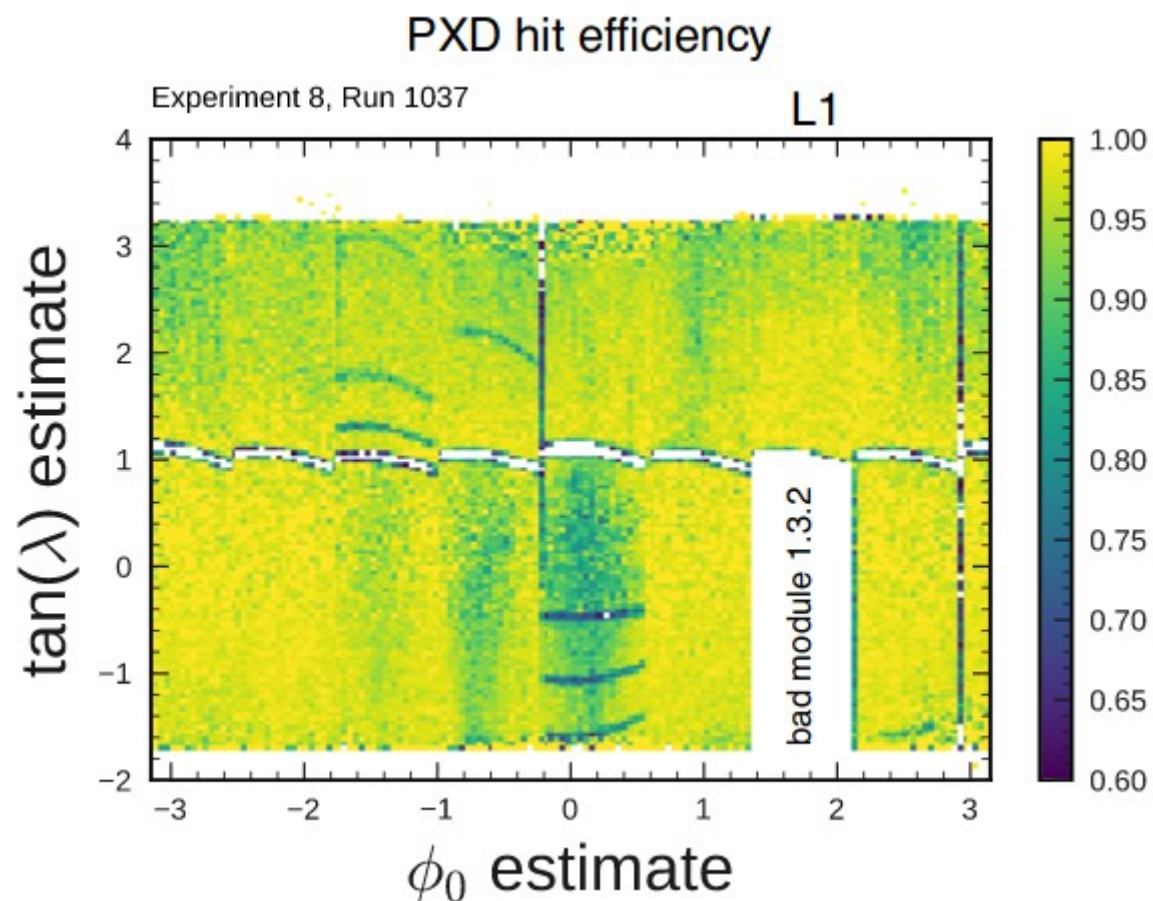
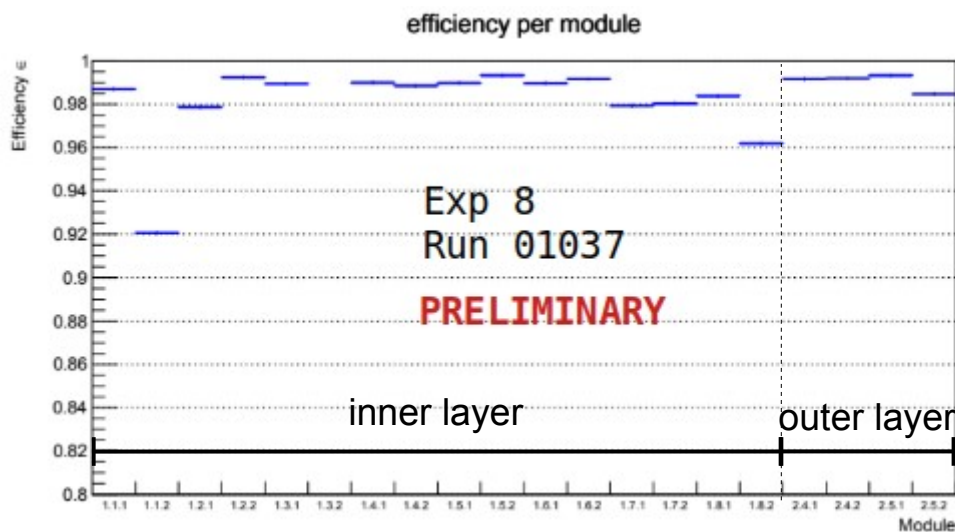
Compensation for Radiation Damage

- MPV for cluster changes with irradiation
- Expected, must be corrected for by increasing voltages
- Voltages adjusted to have same source current (100 mA) again
- Radiation dose from diamond sensors → scaling needed

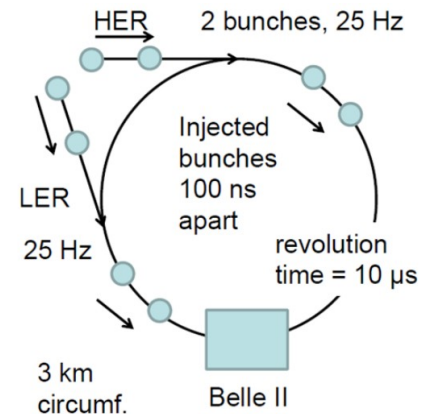
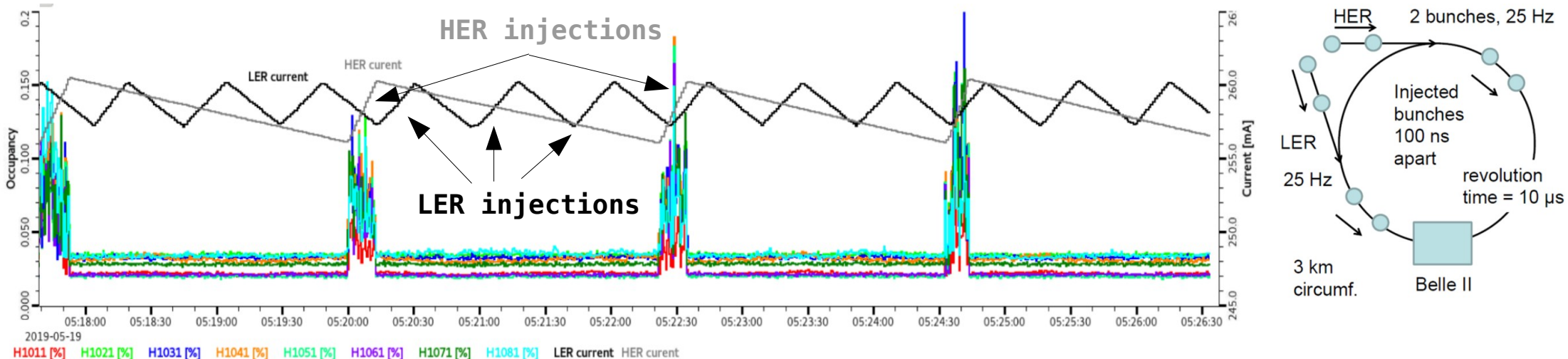


- Defined by hits found close to track intercepting points in modules
- Influenced by
 - Tracking quality
 - Alignment
- Take only tracks with good tracking
 - $p_T > 1 \text{ GeV}/c$

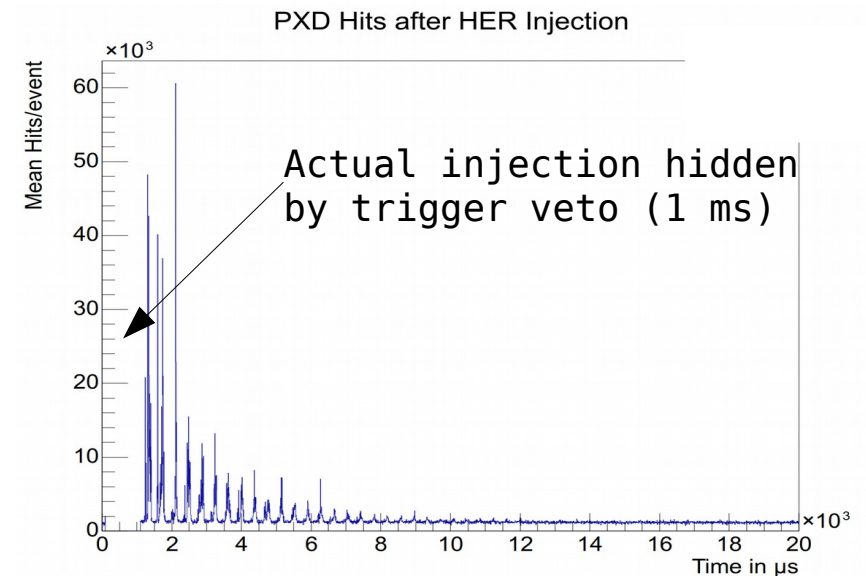
$$\epsilon = \frac{\text{nr of tracks with hit near track intercept}}{\text{nr of good track intercepting a module}}$$



Continuous Injection Backgrounds

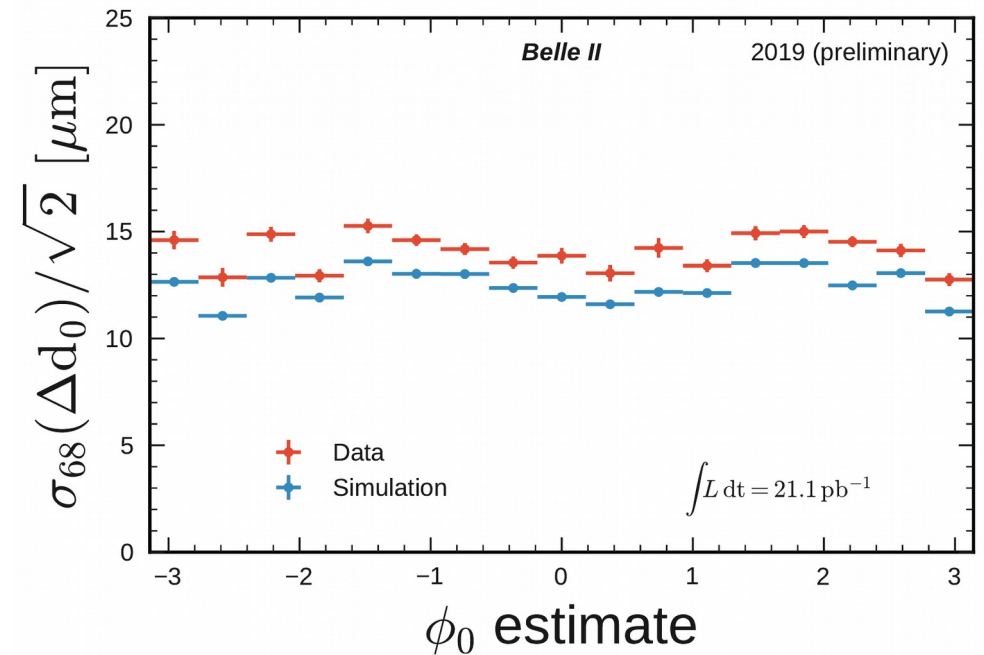
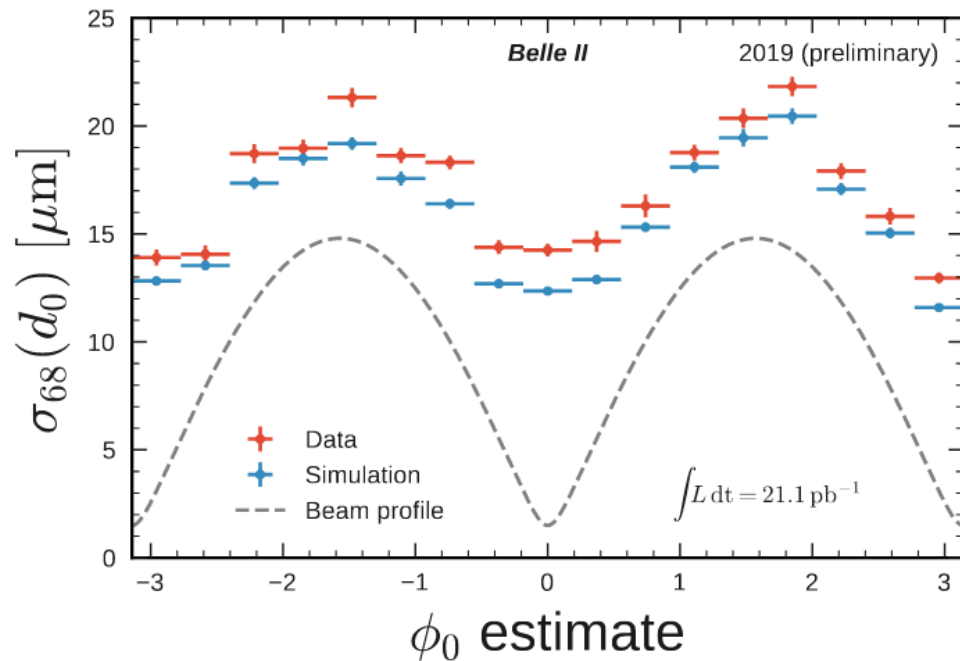


- Increased luminosity by continuous (top-up) injection, max 50 Hz
- Large background during HER injection (noisy bunch) → can lead to readout problems
- Belle II Trigger Veto (=no readout)
 - Full veto during injection (1-2 ms) and then for ~10 ms each time the bunch passes by (~2 μs)
- For PXD: Possible to blind detector while keeping stored charges (Gated Mode)
 - Deploy for upcoming autumn run



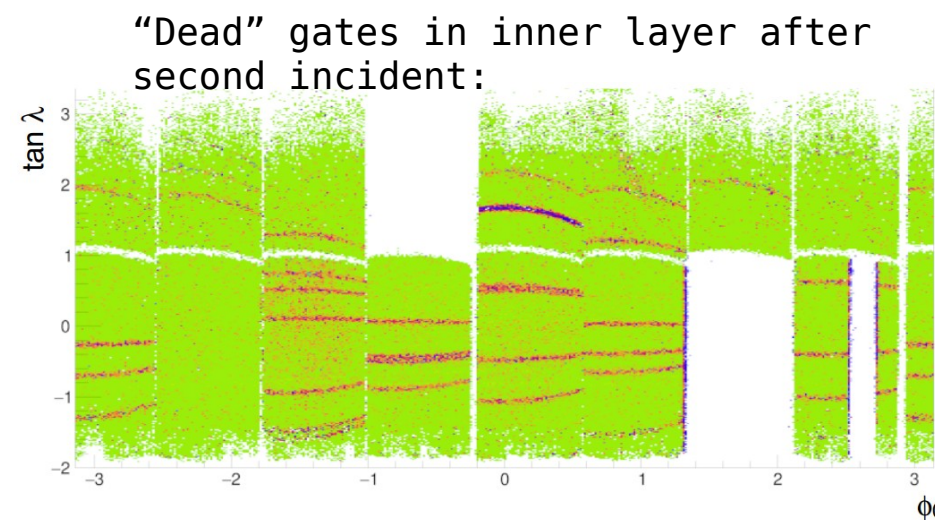
Rolling shutter! Integrated over 20 μs.

- Measuring the point of closest approach from particles from the interaction point in x, y
- Vertex resolution with PXD is close to MC expectations
 - d_0 resolution of $14.5 \mu\text{m}$ achieved
- Details → T. Bilka: Belle II Vertex Detector Performance

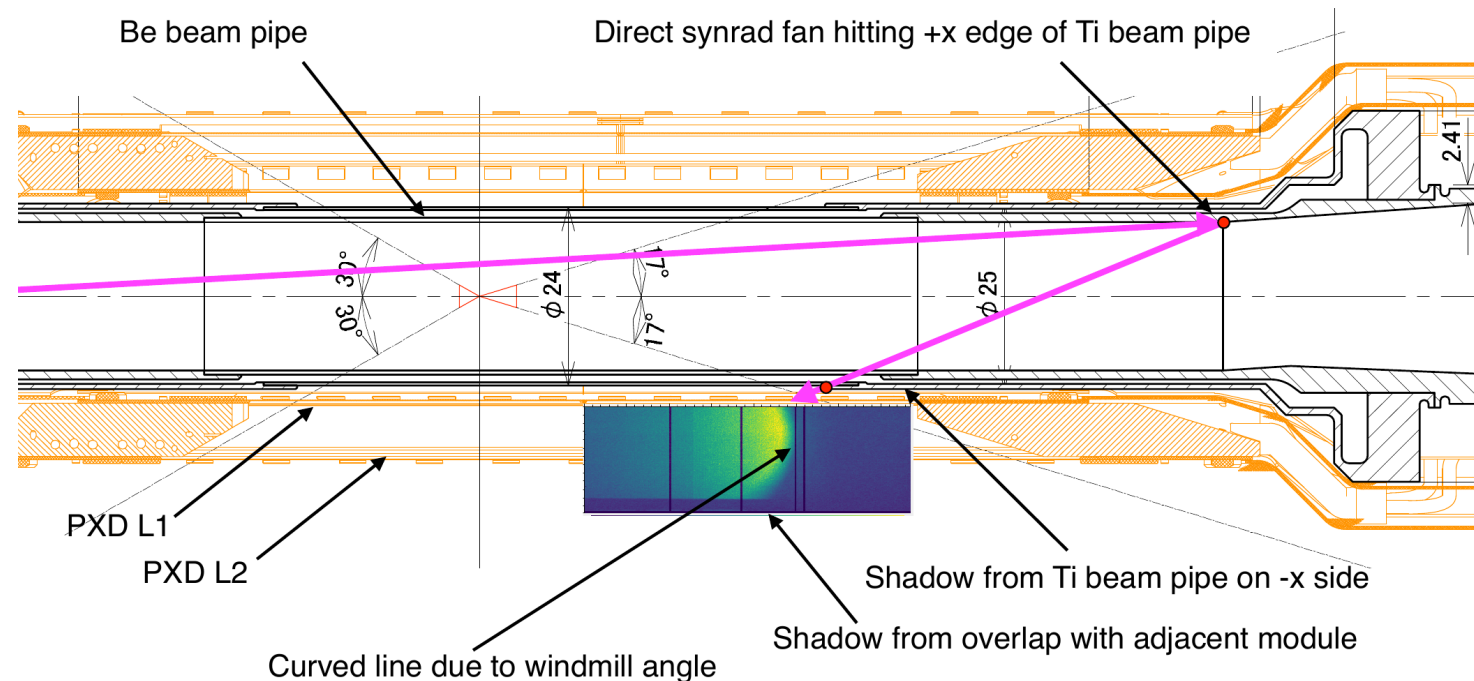


- Two major incidents:
 - QCS power supply failure
 - Beam dust particles event(?), collimator damaged
- Beam particles hitting QCS → magnet quench
 - Large instant radiation burst before beam was dumped (3 rad in <40us)
 - PXD modules in current limit → emergency shutdown
- Working point shifted
- Two modules could not be turned on (large currents)
 - One could be recovered after few days
 - Second module only after summer shutdown
- Permanent damage: “dead” gates
 - Single Event Effect (SEE)
 - → dedicated irradiation test for ASICs and sensor in November

QCS:
Superconducting
quadrupole coils close to
interaction point



- Large photon background was observed for some runs in a few modules in -X
- IR designed such that no direct SR photons hit the central Be beam pipe
 - Secondary photons!
 - Single pixels, low energy
 - Problem: Inhomogeneous irradiation
 - Reason: Change in accelerator “tune”
 - We can only see this if the detector is on

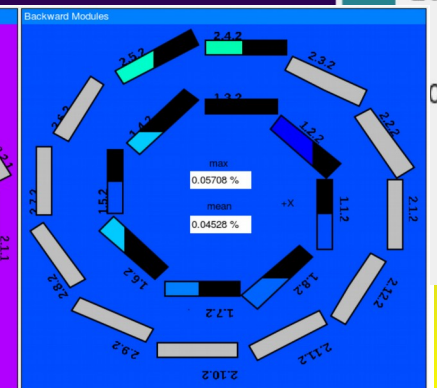
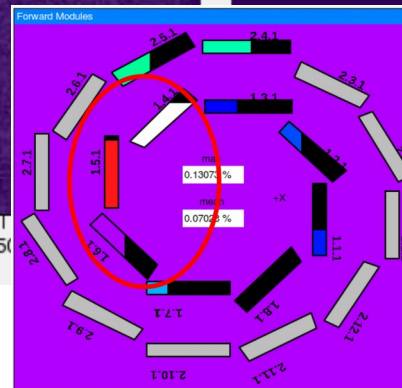
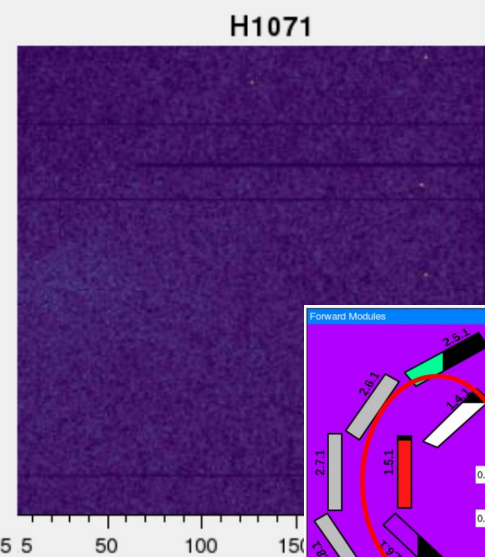
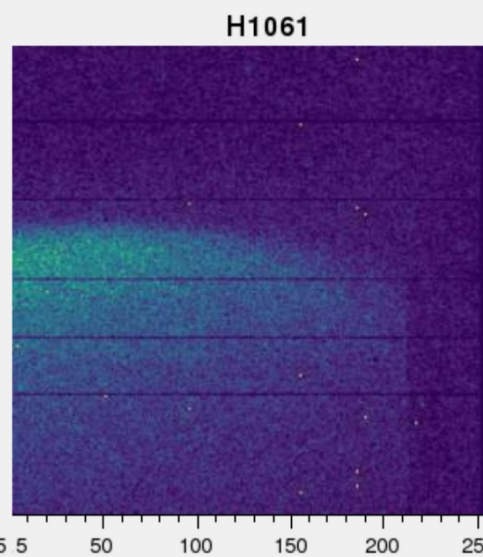
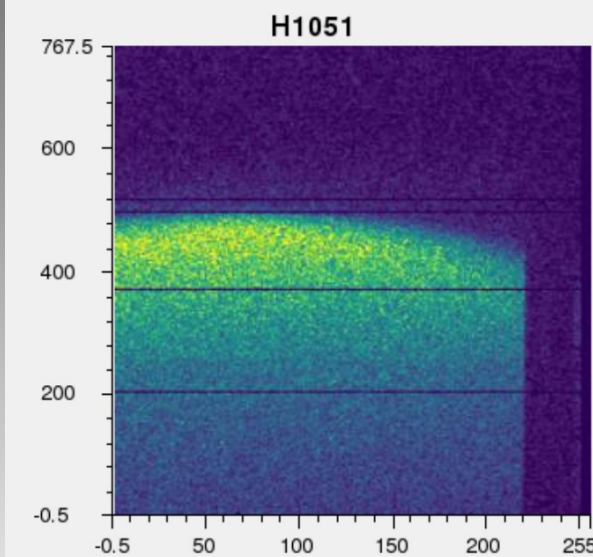
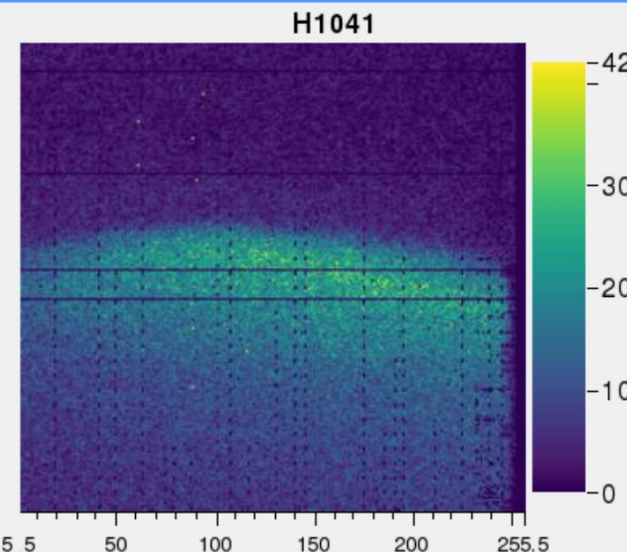
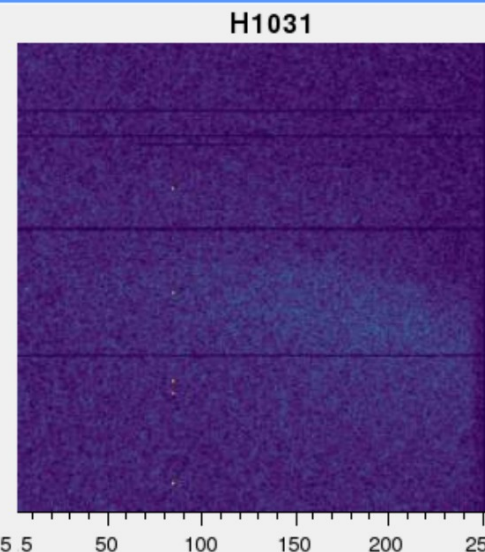
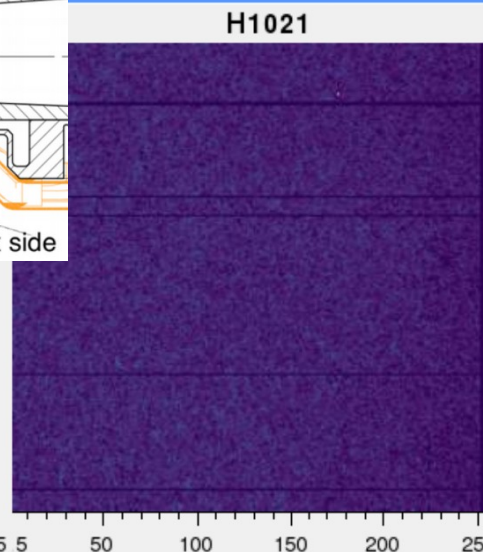
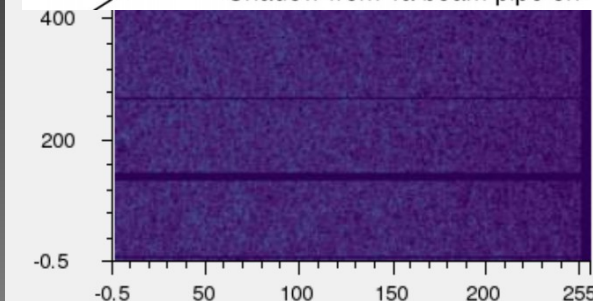
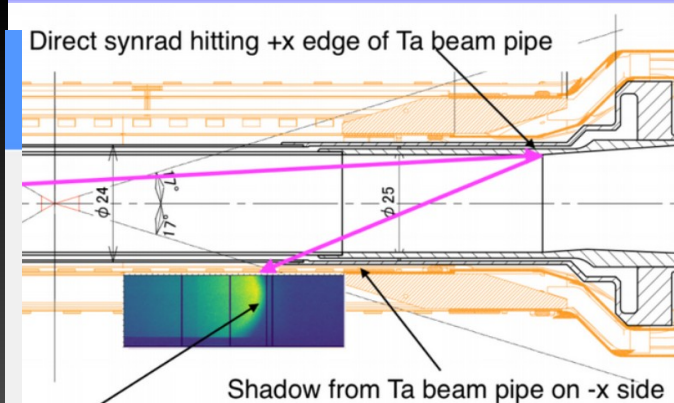


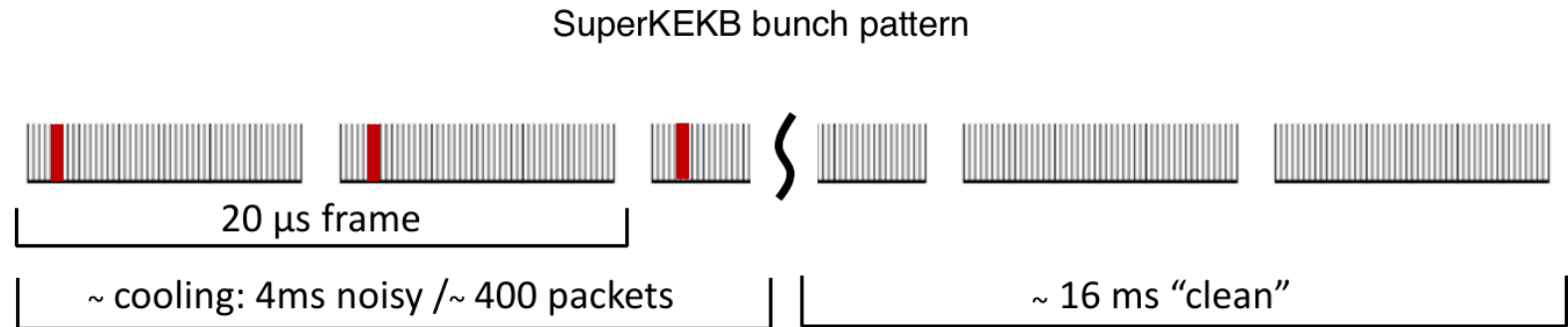
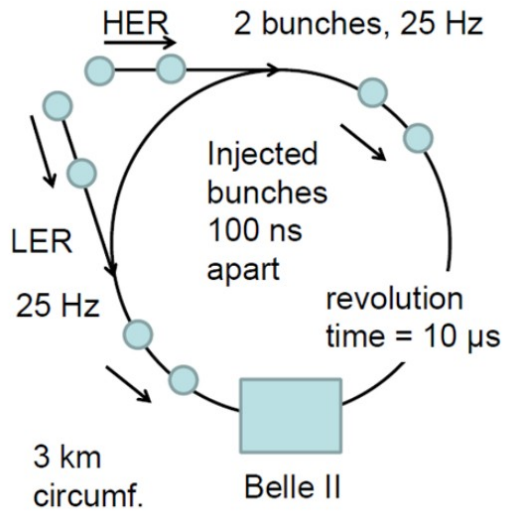
- Belle II first particle physics experiment to use a DEPFET pixel vertex detector
- Good performance demonstrated
 - Some modules not at optimal working point yet
 - Vertex resolution close to MC expectations
- DAQ / ROI data reduction concept proven
- Suffering from damages due to radiation bursts
- Outlook
 - Understand and prevent damage by “beam incidents”
 - Add new collimators!
 - Complete PXD in 2021

- Ch. Schwanda: Performance of the Belle II Silicon Vertex Detector
- T. Bilka: Belle II Vertex Detector Performance

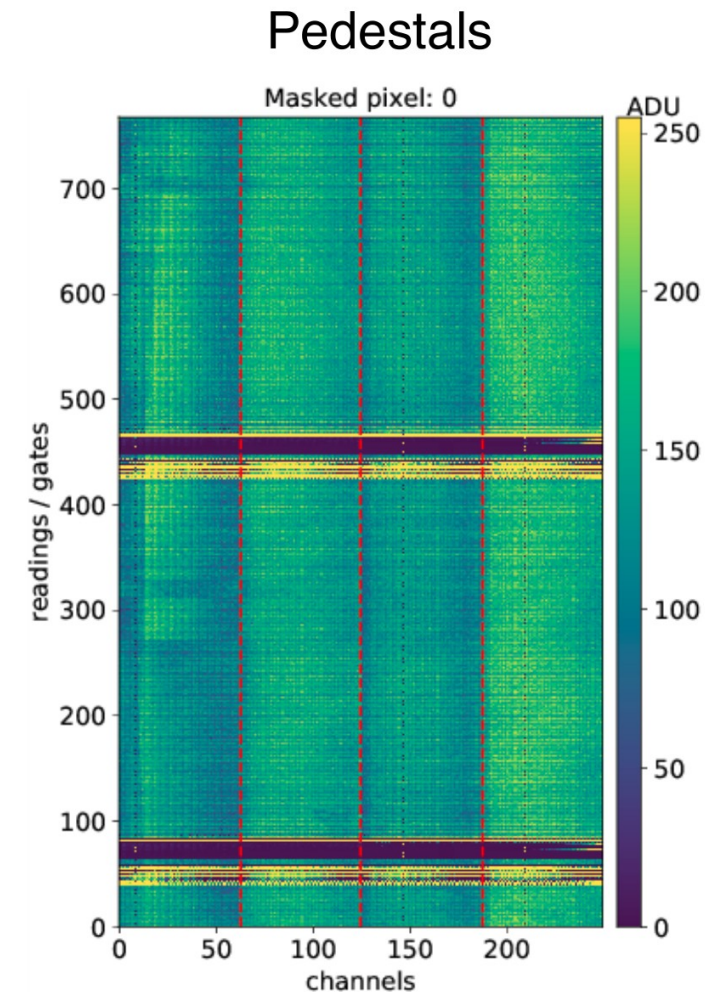
“Synchrotron” Radiation Problem

Problem: Cannot correct for non-uniform rad damage!
We get the damage even if we DO NOT see it because HV is off!!

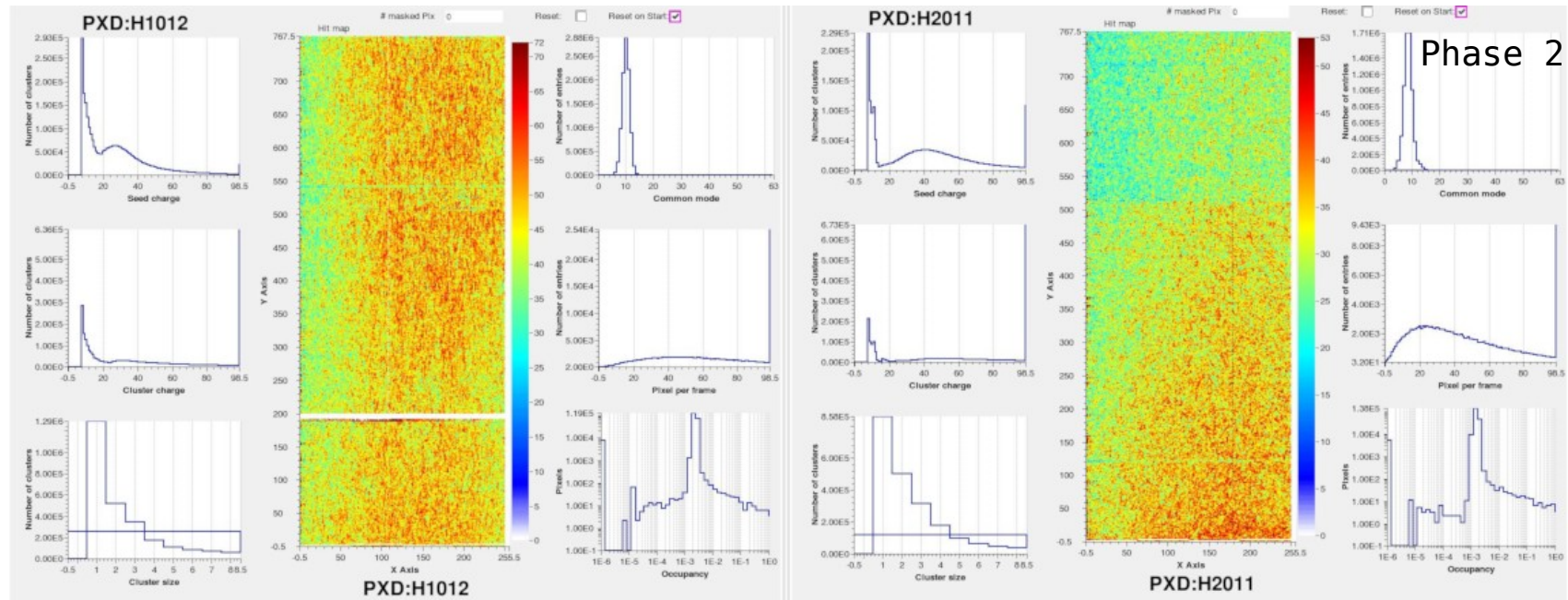




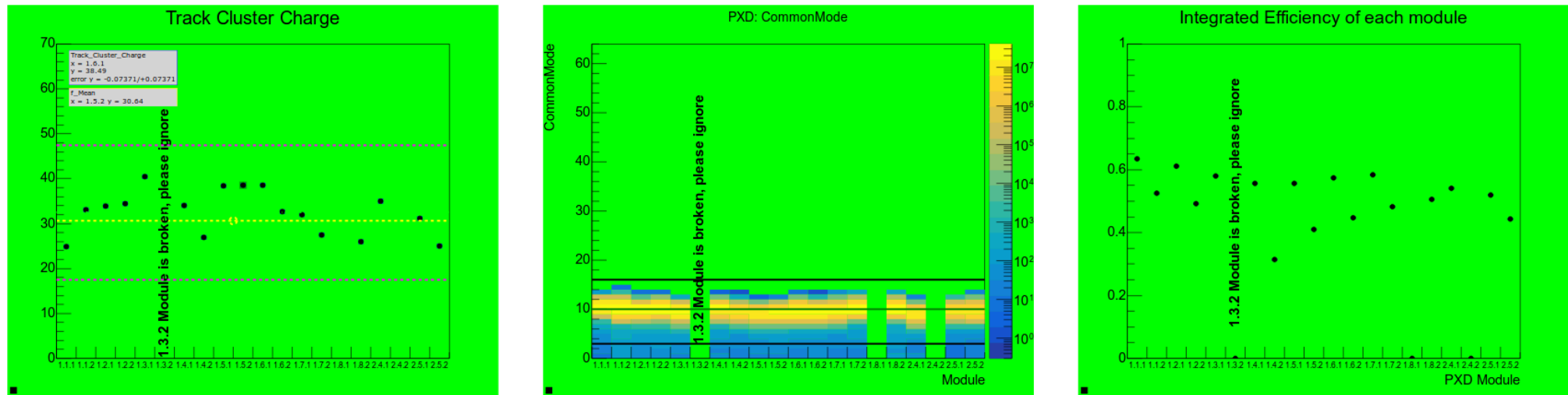
- Gating: change the voltages (potentials) such, that no new charge is collected while preserving the already stored charge.
- Gating two times per readout cycle
- Read out continuous during gating, but the data is unusable
- \rightarrow fraction of the detector area is lost
- Large currents \rightarrow pedestals change



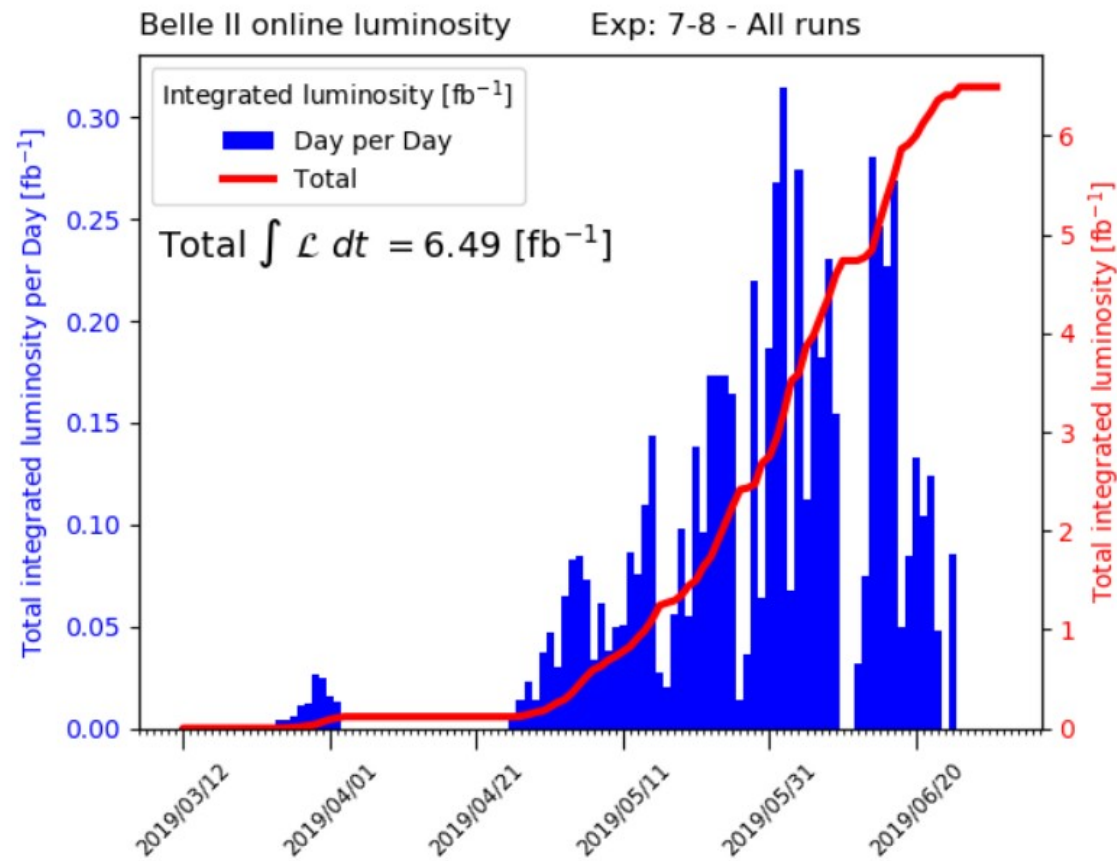
- Histograms from local DAQ



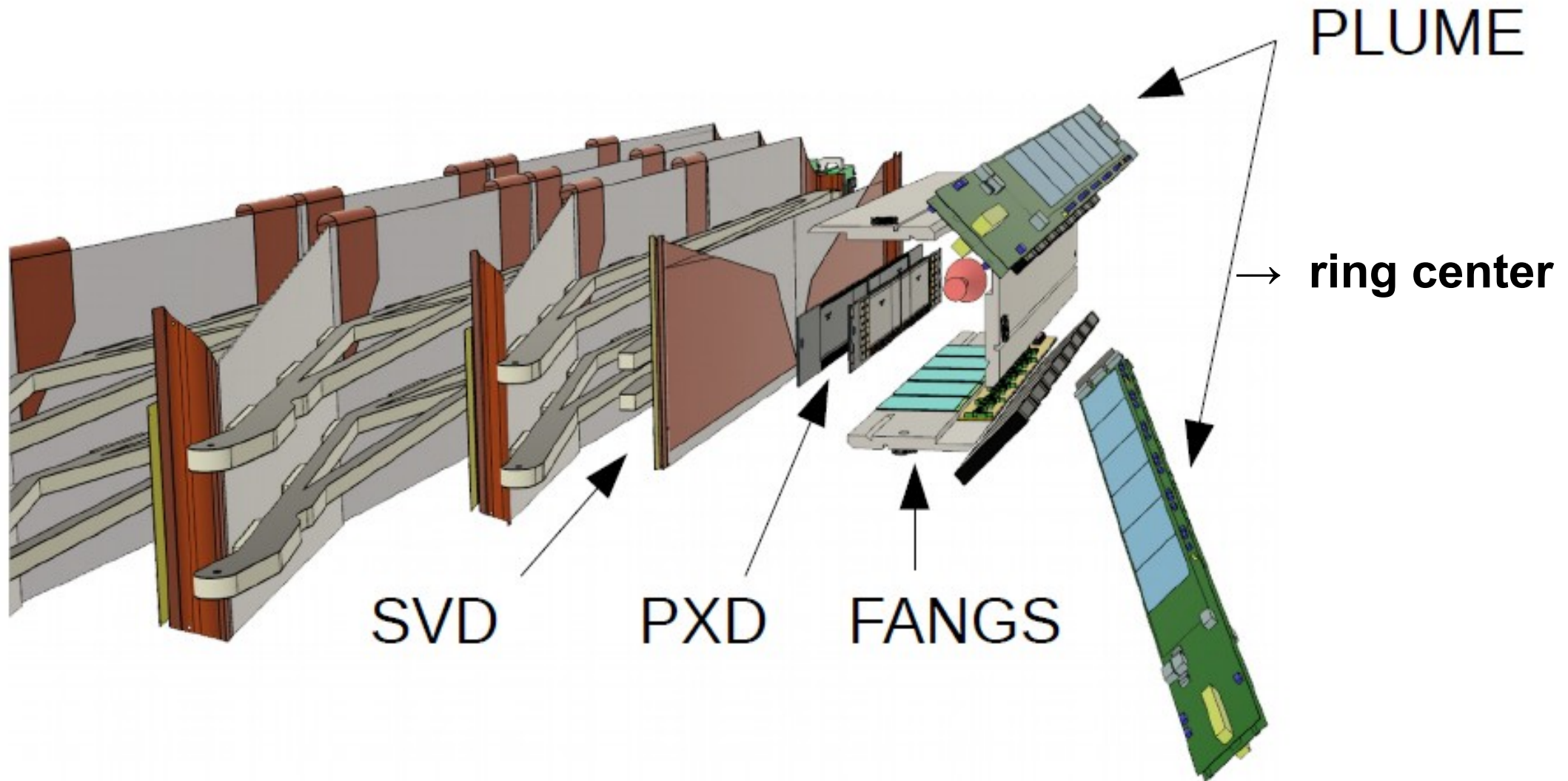
- Histograms from express reconstruction for online monitoring performance



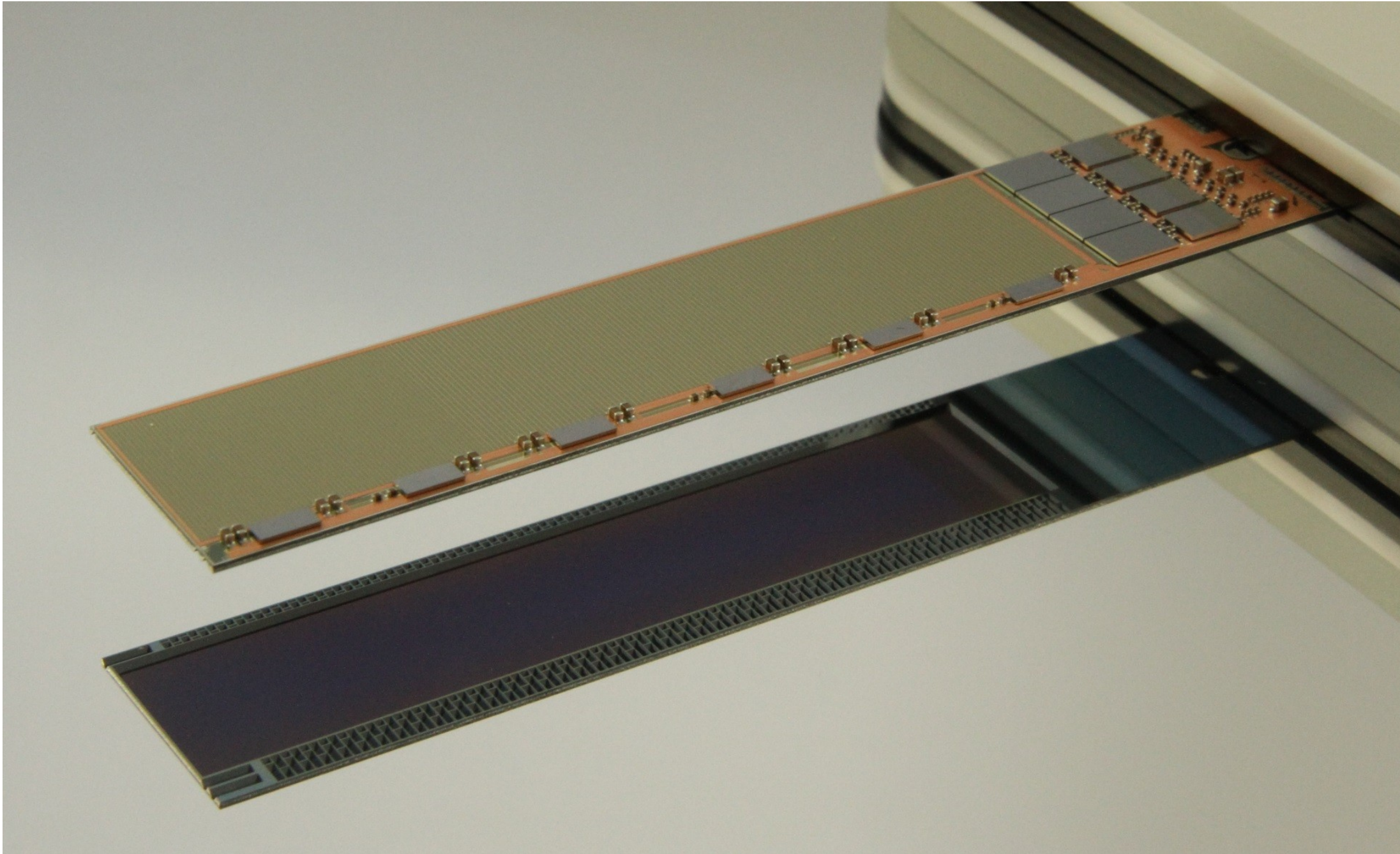
Collected Luminosity in Spring 2019



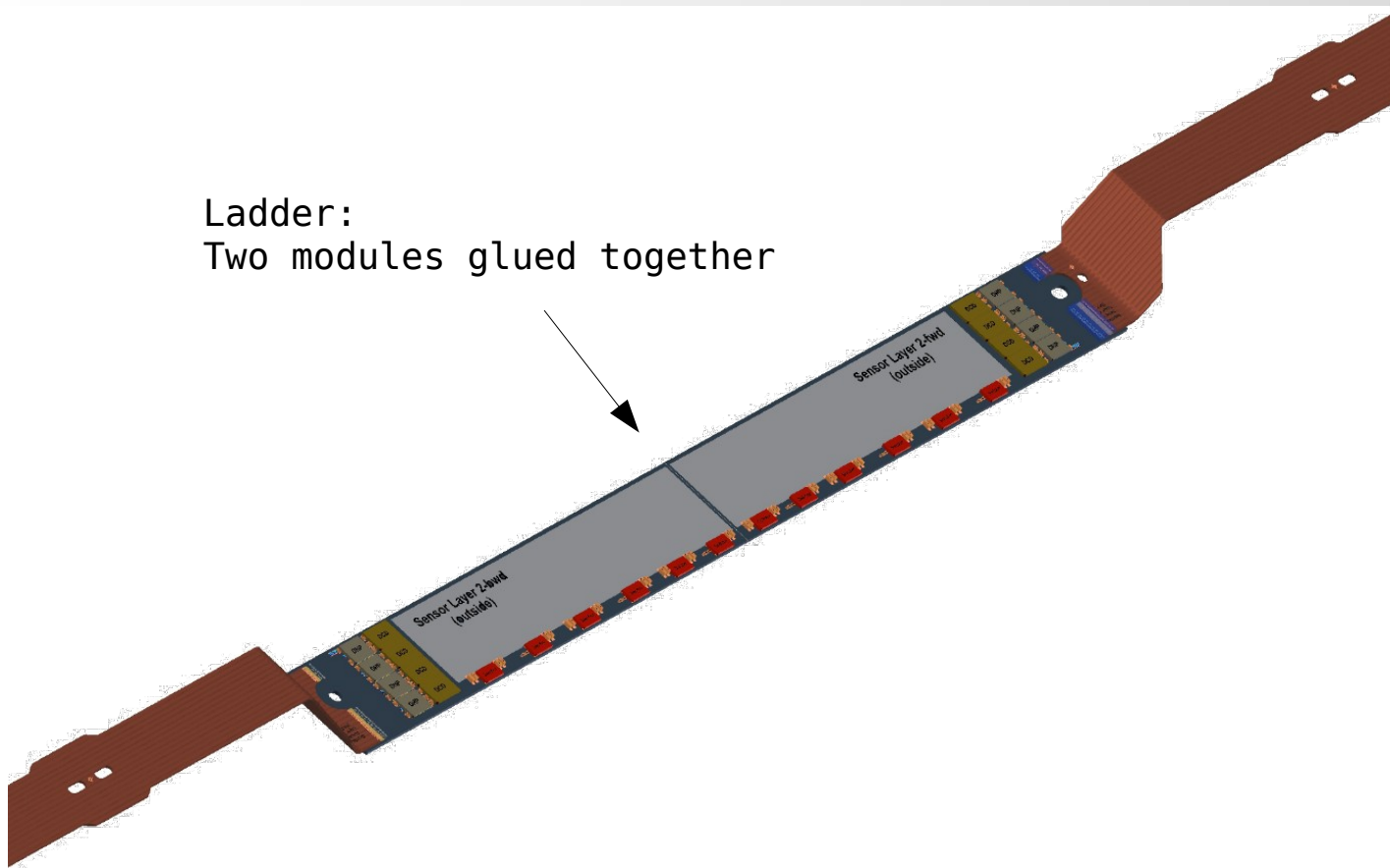




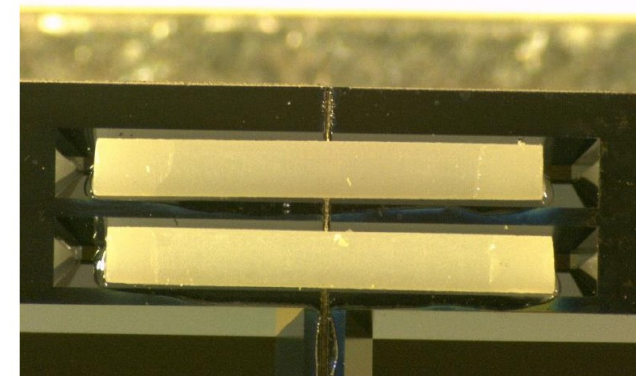
- Occupancy of PXD dominated by background
 - physics $< 1\%$ occupancy
- Beam related background by
 - Synchrotron radiation
 - Beam - gas reactions
 - Touschek effect – intra-beam scattering because of high particle density
- Interaction background
 - Radiative QED, two photon processes
- Can be studied and decomposed with single beams and varying currents
- Big uncertainty in extrapolations
 - Backgrounds much too high (not only in PXD!)
 - LER background dominates
 - Mitigation needed



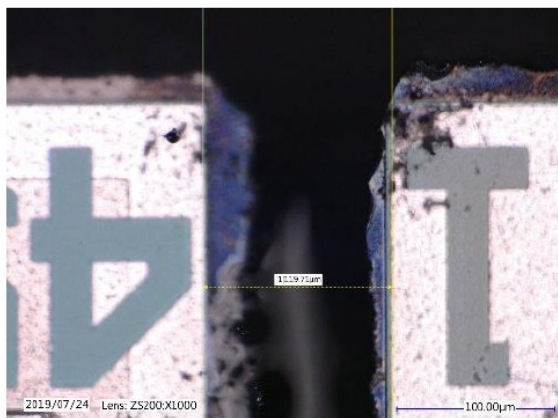
Ladder:
Two modules glued together



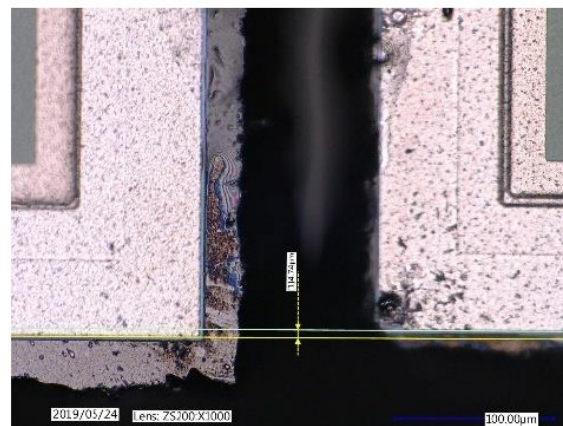
Stiffeners



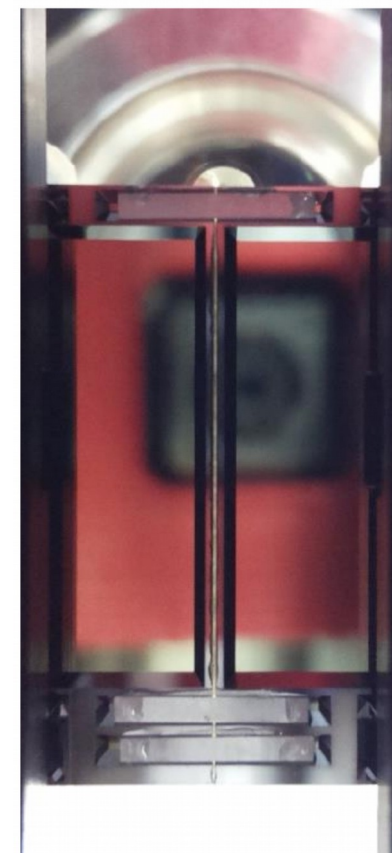
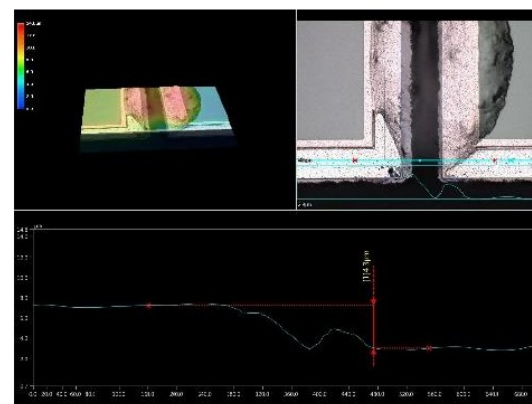
gap: glue gap between Al



dx: lateral displacement



dH: step between modules

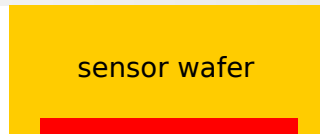


DEPFET Module Production

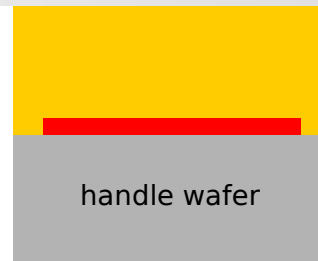
DEPFET



SOI process
(silicon on insulator)



sensor wafer



handle wafer



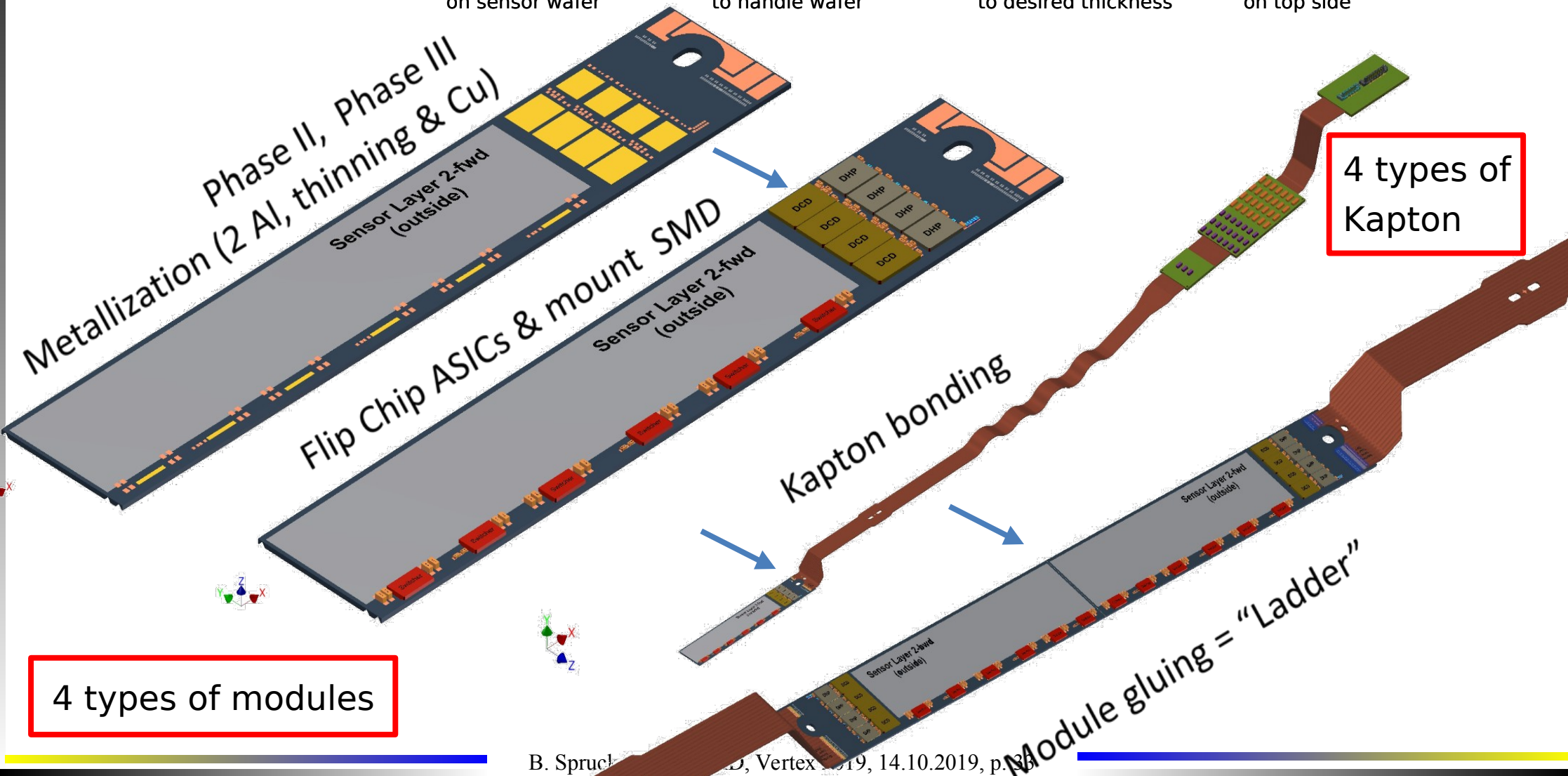
DEPFET Production

1. implant backside
on sensor wafer

2. bond sensor wafer
to handle wafer

3. thin sensor side
to desired thickness

4. process DEPFETs
on top side



4 types of
Kapton

4 types of modules

